Channabasaveshwara Institute of Technology (Affiliated to VTU, Belgaum & Approved by AICTE, New Delhi) (NAAC Accredited & ISO 9001:2015 Certified Institution) NH 206 (B.H. Road), Gubbi, Tumkur – 572 216. Karnataka.	<section-header></section-header>
VLSI LAB	
Sub Code: 21ECL66	
B.E - VI Semester	
Lab Manual 2023-24	
Name :	
USN :	
Batch :Section :	



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# Department of Electronics & CommunicationEngineering

**VLSI LAB** 

Version 2.0

APRIL 2024

# **Prepared by:**

C CUY

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#### INSTITUTION VISION

To create centers of excellence in education and to serve the society by enhancing the quality of life through

value based professional leadership.

#### INSTITUTION MISSION

- 1. To provide high quality technical and professionally relevant education in a diverse learning environment.
- 2. To provide the values that prepare students to lead their lives with personal integrity, professional ethics and civic responsibility in a global society.
- 3. To prepare the next generation of skilled professionals to successfully compete in the diverse global market.
- 4. To promote a campus environment that welcomes and honors women and men of all races, creeds and cultures, values and intellectual curiosity, pursuit of knowledge and academic integrity and freedom.

5. To offer a wide variety of off-campus education and training programmes to individuals and groups.

6. To stimulate collaborative efforts with industry, universities, government and professional societies.

To facilitate public understanding of technical issues and achieve excellence in the operations of the institute.



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#### VISION OF THE DEPARTMENT

"To Nurture and Develop Competent Electronics and Communication Engineering

Skilled Professionals with values for the betterment of Society"

#### MISSION OF THE DEPARTMENT

- 1. To nurture the technical/professional/engineering and entrepreneurial skills for overall self and societal upliftment through co-curricular and extra-curricular events.
- 2. To orient the Faculty/Student community towards the higher education, research and development activities.
- 3. To create the Centres of Excellence in the field of electronics and communication in collaboration with industries/Universities by training the faculty through latest technologies.
- 4. To impart quality technical education in the field of electronics and communication engineering to meet over the current/future global industry requirements.

#### PROGRAM SPECIFIC OUTCOMES

PSO1: Build Analog and Digital Electronic systems for Multimedia Applications, VLSI and

Embedded Systems in Interdisciplinary Research / Development.

PSO2: Design and Develop Communication Systems as per Real Time Applications and Current

Trends.

#### PROGRAM EDUCATIONAL OBJECTIVES

PEO1 : Provide technical solutions to real world problems in the areas of electronics

and communication by developing suitable systems.

PEO2 : Pursue engineering career in Industry and/or pursue higher education and

Research.

PEO3: Acquire and follow best professional, ethical practices in Industry relevant to

the Society.

PEO4 : Communicate effectively and Develop an ability to work in team/Individually



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#### **PROGRAMME OUTCOMES**

1. **Engineering knowledge**: Apply the knowledge of mathematics, science, engineering fundamentals, and an engineering specialization to the solution of complex engineering problems.

2. **Problem analysis**: Identify, formulate, review research literature, and analyze complex engineering problems reaching substantiated conclusions using first principles of mathematics, natural sciences, and engineering sciences.

3. **Design/development of solutions**: Design solutions for complex engineering problems and design system components or processes that meet the specified needs with appropriate consideration for the public health and safety, and the cultural, societal, and environmental considerations.

4. **Conduct investigations of complex problems**: Use research-based knowledge and research methods including design of experiments, analysis and interpretation of data, and synthesis of the information to provide valid conclusions.

5. **Modern tool usage**: Create, select, and apply appropriate techniques, resources, and modern engineering and IT tools including prediction and modeling to complex engineering activities with an understanding of the limitations.

6. **The engineer and society**: Apply reasoning informed by the contextual knowledge to assess societal, health, safety, legal and cultural issues and the consequent responsibilities relevant to the professional engineering practice.

7. **Environment and sustainability**: Understand the impact of the professional engineering solutions in societal and environmental contexts, and demonstrate the knowledge of, and need for sustainable development.

8. **Ethics**: Apply ethical principles and commit to professional ethics and responsibilities and norms of the engineering practice.

9. **Individual and team work**: Function effectively as an individual, and as a member or leader in diverse teams, and in multidisciplinary settings.

10. **Communication**: Communicate effectively on complex engineering activities with the engineering community and with society at large, such as, being able to comprehend and write effective reports and design documentation, make effective presentations, and give and receive clear instructions.

11. **Project management and finance**: Demonstrate knowledge and understanding of the engineering and management principles and apply these to one's own work, as a member and leader in a team, to manage projects and in multidisciplinary environments.

12. Life-long learning: Recognize the need for, and have the preparation and ability to engage in independent and life-long learning in the broadest context of technological change.

	LIST OF LAB EXPERIMENTS	
Exp. No.	Name of the Experiment	Page No.
	ASIC Digital Design	4
	Introduction	1-3
1	4Bit Adder	4-6
	Write Verilog Code	
	Verify the Functionality using Test-bench	
	<ul> <li>Synthesize the design by setting proper constraints and obtain the netlist.</li> </ul>	
	From the report generated identify Critical path, Maximum delay, Totalnumber of cells, Power	
	requirement and Total area required	<u> </u>
2	4 – Bit Booth Multiplier	7 - 9
	<ul> <li>Write Verilog Code</li> <li>Verify the Functionality using Test – bench</li> </ul>	
	<ul> <li>Synthesize the design by setting proper constraints and obtain the netlist.</li> </ul>	
	From the report generated identify Critical path, Maximum delay, Total number of cells, Power	
	requirement and Total area required.	
3	32Bit ALU Supporting 4-Logical and 4-Arithmetic operations, using case and ifstatement for ALU	10 - 13
	Behavioral Modeling	
	Write Verilog Code	
	Verify functionality using Test-bench	
	Synthesize the design targeting suitable library and by setting area and timingconstraints	
	<ul> <li>Tabulate the Area, Power and Delay for the Synthesized netlist</li> </ul>	
	Identify Critical path	
4	Latch and Flip-Flop Synthesize the design and compare the synthesis report (D, SR. JK)	14 - 20
	ASIC Analog Design	<u> </u>
		24 27
5	Introduction & a) Capture the schematic of CMOS inverter with load capacitance of 0.1pF and set the widths of	21 - 27
	Inverter with Wn = Wp, Wn = 2Wp, Wn = Wp/2 and length at selected technology.	
	Carry out the following:	
	i. Set the input signal to a pulse with rise time, fall time of 1ns and pulse width of 10ns and	
	the time period of 20ns and plot the input voltage and output voltage of designed inverter?	,
	ii. From the simulation result compute tpHL, tpLH and td for all three geometrical settings of	
	width?	
	iii. Tabulate the results of delay and find the best geometry for minimum delay for CMOS inverter?	
	b) Draw layout of inverter with Wp/Wn = 40/20, use optimum layout methods. Verify for DRC	
	and LVS, extract parasitic and perform post layout simulations, compare the results with	
	prelayout simulations. Record the observations.	
6		28 – 34
	inverter computed in experiment above. Verify the functionality of NAND gate and also find	
	out the delay td for all four possible combinations of input vectors. Table the results. Increase	
	<ul><li>the drive strength to 2X and 4X and tabulate the results.</li><li>b) Draw the layout of NAND with Wp/Wn = 40/20, use optimum layout methods. Verify for DRC</li></ul>	
	and LVS, extract parasitic and perform post layout simulations, compare the results with	
	prelayout simulations. Record the observations.	
7	a) Capture schematic of Common Source Amplifier with PMOS Current Mirror Load and find its	35 – 39
	transient response and AC response? Measure the Unit Gain Bandwidth (UGB), amplification	-
	factor by varying transistor geometries, study the impact of variation in width to UGB.	
	<b>b)</b> Draw Layout of common source amplifier, use optimum layout methods. Verify for DRC & LVS,	
	extract parasitic and perform post layout simulations, compare the results with pre-layout	
	simulations. Record the observations.	

8	a)	Capture schematics of two-stage operational amplifier and measure the following:	40 – 46
		a. UGB	
		b. dB Bandwidth	
		c. Gain Margin and phase margin with and without coupling capacitance	
		<ul> <li>d. Use the op-amp in the inverting and non-inverting configuration and verify its functionality.</li> </ul>	
		<ul> <li>e. Study the UGB, 3dB bandwidth, gain and power requirement in op-amp by varying the stage wise transistor geometries and record the observations.</li> </ul>	
	b)	Draw layout of two-stage operational amplifier with minimum transistor width set to 300 (in 180/90/45 nm technology), choose appropriate transistor geometries as per the results	
		obtained in part a. Use optimum layout methods. Verify for DRC and LVS, extract parasitic	
		and perform post layout simulations, compare the results with pre-layout simulations.	
		Record the observations.	
		Demonstration Experiments (For CIE)	
9	UART		47 – 54
	•	Write Verilog Code	
	•	Verify the Functionality using Test-bench	
	•	Synthesize the design targeting suitable library and by setting area and timingconstraints	
	•	Tabulate the Area, Power and Delay for the Synthesized netlist Identify Critical path	
10	For sy	nthesized netlist carry out the following:	55 – 84
	•	Floor planning	
	•	Placement and Routing	
	•	Record the parameters such as no. of metal layers used for routing, flip method for	
		placement of standard cells	
	•	Physical Verification and record the DRC and LVS reports	
		Generate GDSII	

		SYLLABUS		
		VLSI Laboratory		
Course Co	de	21ECL66	CIE Marks	50
Teaching I	Hours/Week (L: T: P: S)	0:0:2:0	SEE Marks	50
Credits		1	Exam Hours	3
Sl.No.		Experiments		
		ASIC Digital Design		
1	From the report generated identify (	est-bench proper constraints and obtain the ne Critical path, Maximum delay, Total n		errequirement and Total
2		est-bench proper constraints and obtain the ne Critical path, Maximum delay, Tota		Power requirement and
3	Modeling • Write Verilog Code • Verify functionality using Test-b	suitable library and by setting area a		
4		pare the synthesis report (D, SR, JK)		
		ASIC Analog Design		
5		inverter with load capacitance of 0 nd length at selected technology.	.1pF and set the w	idths ofInverter with Wn
	of 20ns and plot the in ii. From the simulation re iii. Tabulate the results of b) Draw layout of inverter with Wp	pulse with rise time, fall time of 1ns put voltage and output voltage of de sult compute tpHL, tpLH and td for al delay and find the best geometry for /Wn = 40/20, use optimum layout m ut simulations, compare the results v ervations.	signed inverter? Il three geometrical minimum delay fou ethods. Verify for D	settings of width? r CMOS inverter?
6	<ul> <li>a) Capture the schematic of 2-inperiment above. Verify the combinations of input vectors results.</li> <li>b) Draw the layout of NAND with</li> </ul>	out CMOS NAND gate having similar functionality of NAND gate and also s. Table the results. Increase the dri Wp/Wn = 40/20, use optimum layou orm post layout simulations, compare	o find out the dela ve strength to 2X ut methods. Verify f	y td for all four possible and 4X and tabulate the or DRC
7	<ul> <li>a) Capture schematic of Common and AC response? Measure geometries, study the impact o</li> <li>b) Draw Layout of common source</li> </ul>	Source Amplifier with PMOS Current the Unit Gain Bandwidth (UGB), f variation in width to UGB. e amplifier, use optimum layout met tions, compare the results with pre-I	amplification factor hods. Verify for DR	or by varying transistor C & LVS, extract parasitic

	a) Capture schematics of two-stage operational amplifier and measure the following:
	i. UGB
	ii. dB Bandwidth
	iii. Gain Margin and phase margin with and without coupling capacitance
	iv. Use the op-amp in the inverting and non-inverting configuration and verify its functionality.
	v. Study the UGB, 3dB bandwidth, gain and power requirement in op-amp by varying the stage wise
	transistor geometries and record the observations.
	b) Draw layout of two-stage operational amplifier with minimum transistor width set to 300 (in 180/90/45 nr
	technology), choose appropriate transistor geometries as per the results obtained in part a. Use optimum layou
	methods. Verify for DRC and LVS, extract parasitic and perform post layout simulations, compare the results wit
	pre-layout simulations. Record the observations.
	Demonstration Experiments ( For CIE )
9	UART
	Write Verilog Code
	<ul> <li>Verify the Functionality using Test-bench</li> </ul>
	<ul> <li>Synthesize the design targeting suitable library and by setting area and timing constraints</li> </ul>
	Tabulate the Area, Power and Delay for the Synthesized netlist, Identify Critical path
10	For synthesized netlist carry out the following:
	Floor planning
	Placement and Routing
	Record the parameters such as no. of metal layers used for routing, flip method for placement of standard cells
	<ul> <li>Physical Verification and record the DRC and LVS reports</li> </ul>
	Generate GDSII
11	Design and characterize 6T binary SRAM cell and measure the following:
	Read Time, Write Time, SNM, Power
	• Draw Layout of 6T SRAM, use optimum layout methods. Verify for DRC & LVS, extract parasitic and perform post
	layout simulations, compare the results with pre-layout simulations. Record the observations.
ssessme	nt Details (both CIE and SEE)
	htage of Continuous Internal Evaluation (CIE) is 50% and for Semester End Exam (SEE) is 50%. The minimum
assing n	nark for the CIE is 40% of the maximum marks (20 marks). A student shall be deemed to have satisfied the academic
assing m equirem	hark for the CIE is 40% of the maximum marks (20 marks). A student shall be deemed to have satisfied the academic ents and earned the credits allotted to each course. The student has to secure not less than 35% (18 Marks out of
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#### Semester End Evaluation (SEE):

SEE marks for the practical course is 50 Marks.

SEE shall be conducted jointly by the two examiners of the same institute, examiners are appointed by the University All laboratory experiments are to be included for practical examination.

(Rubrics) Breakup of marks and the instructions printed on the cover page of the answer script to be strictly adhered to by the examiners. **OR** based on the course requirement evaluation rubrics shall be decided jointly by examiners.

Students can pick one question (experiment) from the questions lot prepared by the internal /external examiners jointly. Evaluation of test write-up/ conduction procedure and result/viva will be conducted jointly by examiners.

General rubrics suggested for SEE are mentioned here, writeup-20%, Conduction procedure and result in -60%, Viva-voce 20% of maximum marks. SEE for practical shall be evaluated for 100 marks and scored marks shall be scaled down to 50 marks (however, based on course type, rubrics shall be decided by the examiners).

Change of experiment is allowed only once and 15% Marks allotted to the procedure part to be made zero.

The duration of SEE is 03 hours.

Rubrics suggested in Annexure-II of Regulation book



(Affiliated to VTU, Belgaum & Approved by AICTE, New Delhi) (NAAC Accredited & ISO 9001:2015 Certified Institution) NH 206 (B.H. Road), Gubbi, Tumkur – 572 216. Karnataka.



#### **Department of Electronics and Communication Engineering**

VLSI LAB Course Objectives and Outcomes

Course objectives: This course will enable students to:

- > Design, model, simulate and verify digital circuits.
- > Design layouts and perform physical verification of CMOS digital circuits.
- > Perform ASIC design flow and understand the process of synthesis, synthesis constraints and evaluating the synthesis reports to obtain optimum gate level netlist.
- > Perform RTL-GDSIL flow and understand the stages in ASIC.

**Course outcomes:** After studying this course, students will be able to:

> Design and simulate combinational and sequential digital circuits using Verilog HDL.

- Understand the synthesis process of digital circuits using EDA tool.
- > Perform ASIC design flow and understand the process of synthesis, synthesis constraints and evaluating the synthesis reports to obtain optimum gate level netlist.
  - > Design and simulate basic CMOS circuits like inverter, common source amplifier, differential amplifier,

#### SRAM.

> Perform RTL\_GDSII flow and understand the stages in ASIC design.

#### **INSTRUCTIONS TO THE STUDENT**

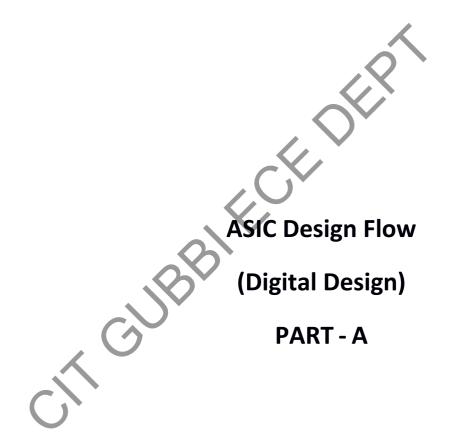
- 1. Come prepared to the lab with relevant theory about the experiment you are conducting.
- 2. Each experiment will be evaluated for 20 marks. More weightage will be given for preparation and understanding.
- 3. Handle the desktop system and interfacing boards with care
- 4. Do not delete or change the system settings and files.
- 5. For any missing items, penalty will be imposed on the respective batch.

6. Maintain professional attitude and discipline during lab sessions.

## INTRODUCTION

VLSI stands for Very Large Scale Integration, which is a technology used to create integrated circuits (ICs) by combining thousands or millions of transistors into a single chip. VLSI technology has revolutionized the electronics industry by enabling the production of compact, powerful and low-cost microprocessors, memory chips, digital signal processors, and other advanced electronic devices.

As of 2020, the scale of integration in VLSI technology has reached nanometer level processes, with feature sizes on the order of 7-5 nm, allowing for the integration of billions of transistors on a single chip. The latest processors and integrated circuits are being manufactured using 7nm and 5nm process nodes, enabling greater performance and power efficiency.



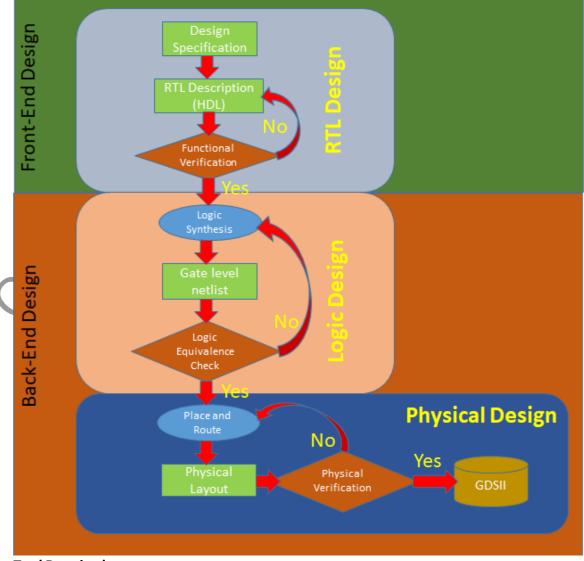
What Is an ASIC ?

An ASIC (Application-Specific Integrated Circuit) is a type of integrated circuit (IC) that is designed to perform a specific task or function. It is customized for a particular application, unlike general-purpose ICs such as microprocessors and memory chips.

ASICs are typically used in high-performance applications where specific processing requirements need to be met, such as in networking, telecommunications, and consumer electronics. ASICs are designed and manufactured for a specific customer or application and can include digital, analog, and mixed-signal components on a single chip.

The complete ASIC design process can be divided into two parts.

- 1. Front End Design
- 2. Back End Design



#### **Tool Required:**

- Functional Simulation: Incisive Simulator (ncvlog, ncelab, ncsim)
- Synthesis: Genus

# Lab 1: 4-Bit Adder

Aim: To write a verilog code for 4bit adder and verify the functionality using Test bench.

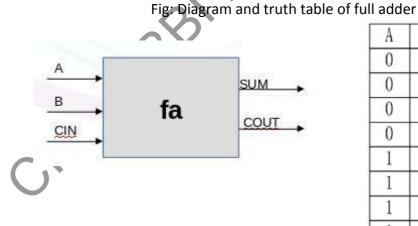
- Synthesize, Analyse Reports and Netlist, Critical Path and Max Operating Frequency.
- From the report generated find the total number of cells, power requirement and total area requirement.

## **Tool Required:**

- Functional Simulation: Incisive Simulator (ncvlog, ncelab, ncsim)
- Synthesis: Genus

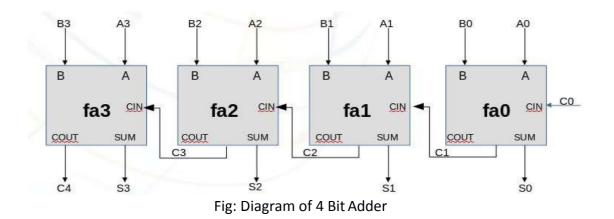
# Design Information and Bock Diagram:

A full adder is a combinational circuit that performs the arithmetic sum of three input bits Ai, addend Bi and carry in C in from the previous adder. Its results contain the sum Si and the carryout, C out to the next stage. So to design a 4-bit adder circuit we start by designing the 1 –bit full adder then connecting the four 1-bit full adders to get the 4-bit adder as shown in the diagram below. For the 1-bit full adder, the design begins by drawing the Truth Table for the three input and the corresponding output SUM and CARRY.



		-	r	1
A	B	С	SUM OUT	CARRY OUT
0	0	0	0	0
0	0	1	1	0
0	1	0	1	0
0	1	1	0	1
1	0	0	1	0
1	0	1	0	1
1	1	0	0	1
1	1	1	1	1

2023-2024

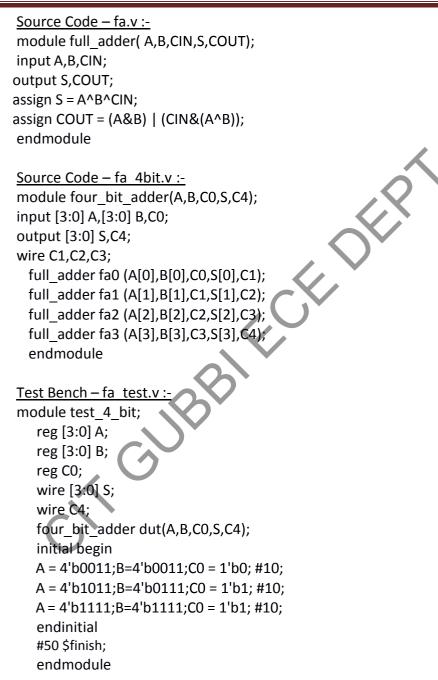


#### Creating a Work space :

• Create a new sub-Directory for the Design and open a terminal from the Sub-Directory.

# a) Verify the Functionality

- Three Codes shall be written for implementation of 4-bit Adder as follows,
  - fa.v → Single Bit 3-Input Full Adder [Sub-Module / Function]
  - fa\_4bit.v  $\rightarrow$  Top Module for Adding 4-bit Inputs.
  - fa\_test.v → Test bench



#### Waveform :

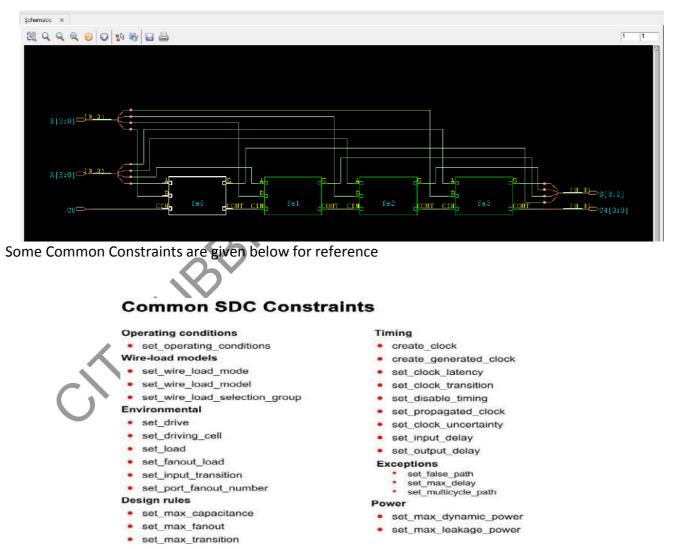
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# b) Synthesis and Report/Output Analysis Note 1:-

1. The Cells given in the netlist can be checked in the .lib files for their properties.

2. The Max Operating Frequency does not apply for Purely Combinational Circuit.

# Synthesis RTL Schematic :



#### <u>Note 2:-</u>

- 1. You can tabulate Area, Power and Timing Constraints using any of the SDC Constraints asinstructed.
- 2. Make sure, during synthesis the Report File Names are changed so that the latest reports donot overwrite the earlier ones.

# Lab 2: 4 – Bit Booth Multiplier

Aim: To write a verilog code for 4bit Booth Multiplier and verify the functionality using Test bench.

- Synthesize, Analyse Reports and Netlist, Critical Path and Max Operating Frequency.
- From the report generated find the total number of cells, power requirement and total area requirement.

#### **Tool Required:**

- Functional Simulation: Incisive Simulator (ncvlog, ncelab, ncsim)
- Synthesis: Genus

#### Design Information and Bock Diagram:

In Booth's multiplier works on Booth's Algorithm that does the multiplication of 2's complement notation of two signed binary numbers.

#### Advantages:

- 1. Less complexity
- 2. Faster Multiplication
- 3. Consecutive additions are replaced
- 4. Ease in scaling

#### Disadvantage:

- 1. High power consumption
- 2. Large chip area

#### Algorithm:

Registers used: A, M, Q, Qres (Qres is the residual bit after a right shift of Q), n (counter)

**Step 1:** Load the initial values for the registers.

A = 0 (Accumulator), Qres = 0, M = Multiplicand, Q = Multiplier and n is the count value which equals the number of bits of multiplier.

Step 2: Check the value of {Q0, Qres}. If 00 or 11, goto step 5. If 01, goto step 3. If 10, goto step 4.

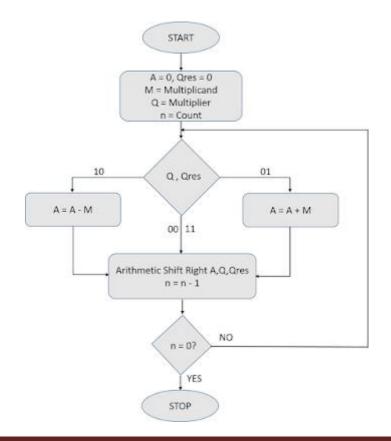
**Step 3:** Perform A = A + M. Goto step 5.

Step 4: Perform A = A - M.

**Step 5:** Perform Arithmetic Shift Right of {A, Q, Qres} and decrement count.

Step 6: Check if counter value n is zero. If yes, goto next step. Else, goto step 2.

Step 7: Stop



#### Creating a Work space :

• Create a new sub-Directory for the Design and open a terminal from the Sub-Directory.

#### a) To Verify the Functionality using Test Bench

```
Source Code - boothmul.v :-
   module BoothMulti (X, Y, Z);
   input signed [3:0] X, Y;
   output signed [7:0] Z;
                                    E-CF-DF-P
   reg signed [7:0] Z;
   reg [1:0] temp;
   integer i;
   reg E1;
   reg [3:0] Y1;
    always @ (X, Y)
        begin
        Z = 8'd0;
        E1 = 1'd0;
        for (i = 0; i < 4; i = i + 1)
                begin
                 temp = {X[i], E1};
                Y1 = -Y;
                case (temp)
                  2'd2 : Z [7 : 4] = Z [7 : 4] + Y1;
                 2'd1 : Z [7 : 4] = Z [7 : 4] + Y;
                 default : begin end
              endcase
   Z = Z >> 1;
   Z[7] = Z[6];
   E1 = X[i];
      end
   if (Y == 4'd8)
      begin
        Z = - Z;
      end
 end
endmodule
Test Bench - boothmul test.v :-
module BoothTB;
  // Inputs
  reg [3:0] X;
  reg [3:0] Y;
  // Outputs
  wire [7:0] Z;
  // Instantiate the Unit Under Test (UUT)
  BoothMulti uut (
    .X(X),
    .Y(Y),
    .Z(Z)
  );
  initial begin
  // Initialize Inputs
    X = 0;
    Y = 0;
 // Wait 100 ns for global reset to finish
```

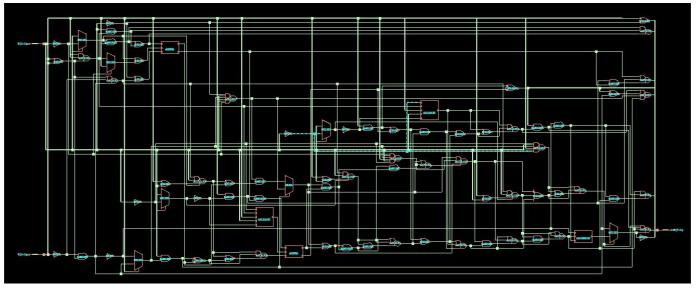
#10;	
X=-5;	
Y=7;	
#100;	
X=-4;	
Y=6;	
#100;	
X=-5;	
Y=-5; // Add stimulus here end	
// Add stimulus here	
end	
Waveform :	
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TimeA → = 300       > Ins→ Pe+ → + + + + + + + + + + + + + + + + + +	TimeA = 300ns

## b) Synthesis and Report/Output Analysis

#### <u>Note 1:-</u>

- 1. The Cells given in the netlist can be checked in the .lib files for their properties.
- 2. The Max Operating Frequency does not apply for Purely Combinational Circuit.

Synthesis RTL Schematic :



Some Common Constraints are given below for reference

# Lab 3 : 32-bit ALU

<u>Aim</u>: Write a verilog code for 32 bit ALU supporting four logical and four arithmetic operations, use case statement and if statement for ALU behavioral modeling.

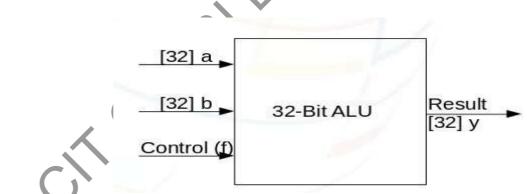
- To Verify the Functionality using Test Bench
- Synthesize and compare the results using if and case statements
- Identify Critical Path and constraints

## **Tool Required:**

- Functional Simulation: Incisive Simulator (ncvlog, ncelab, ncsim)
- Synthesis: Genus

#### Design Information and Bock Diagram:

The ALU will take in two 32-bit values, and control line. An Arithmetic unit does the following task like addition subtraction, multi-fiction and logical operations. As the input is given in32 bit we get 32 bit output. The arithmetic will show only one output at a time so a selector is necessary to select one of the operator.



#### Creating a Work space :

• Create a new sub-Directory for the Design and open a terminal from the Sub-Directory.

#### To Verify the Functionality using Test Bench

```
Source Code – Using Case Statement :
module 32bit alu case(a, b, f, y);
input [31:0]a;
input [31:0]b;
input [2:0]f;
output reg [31:0]y;
always @ (*)
begin
case (f)
 3'b000: y=a&b;
                      //AND Operation
 3'b001: y=a|b;
                      //OR Operation
 3'b010: y=~(a&b);
                      //NAND Operation
 3'b011: y=~(a|b);
                      //NOR Operation
 3'b100: y=a+b;
                      //Addition
 3'b101: y=a-b;
                      //Subtraction
 3'b110: y=a*b;
                      //Multiply
 default: y=32'bx;
  endcase
end
endmodule
```

Test Bench : module 32bit\_alu\_case\_tb; reg [31:0]a; reg [31:0]b; reg [2:0]f; wire [31:0]y; BBILL 32bit\_alu\_case test2(.a(a),.b(b),.f(f),.y(y)); initial begin a=32'h0000000; b=32'hFFFFFFF; #10 f=3'b000; #10 f=3'b001; #10 f=3'b010; #10 f=3'b011; #10 f=3'b100; #10 f=3'b101; #10 f=3'b110; end initial #50 \$finish; endmodule Source Code - Using If Statement : module 32bit\_alu\_if(y,a,b,f); input [31:0]a; input [31:0]b; input [2:0]f; output reg [31:0]y; always@(\*) begin if(f==3'b000) y=a&b; //AND Operation else if (f==3'b001) y=a|b; //OR Operation else if (f==3'b010) //Addition y=a+b;else if (f==3'b011) //Subtraction y=a-b; else if (f==3'b100) //Multiply y=a\*b; else y=32'bx; end endmodule Test bench : module 32bit\_alu\_tb\_if; reg [31:0]a; reg [31:0]b;

reg [2:0]f; wire [31:0]y; 32bit_alu_if test(.y(y),.a(a),.b(b),.f(f)); initial begin a=32'h00000000;
b=32'hFFFFFFF;
#10 f=3'b000;
#10 f=3'b001;
#10 f=3'b010;
#10 f=3'b100;
end
initial
#50 \$finish;
endmodule
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#### a) Synthesize Design

Run the synthesis Process one time for each code and make sure the output File • names are changed accordingly.

## Synthesis RTL Schematic :

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Fig: Schematic Capture of 32 Bit ALU

#### <u>Note :-</u>

- 1. You can tabulate Area, Power and Timing Constraints using any of the SDC Constraints asinstructed.
- 2. Make sure, during synthesis the Report File Names are changed so that the latest reports donot overwrite the earlier ones.

<u>Aim</u>: Write a verilog code for Latch and Flip-flops (D, SR, JK), Synthesize the design and compare the synthesis report.

#### **Tool Required:**

- Functional Simulation: Incisive Simulator (ncvlog, ncelab, ncsim)
  - Synthesis: Genus

#### Design Information and Bock Diagram:

Latches and flip-flops are the basic elements for storing information. One latch or flip-flopcan store one bit of information. The main difference between latches and flip-flops is that for latches, their outputs are constantly affected by their inputs as long as the enable signal is asserted.

In other words, when they are enabled, their content changes immediately when their inputschange. Flip-flops, on the other hand, have their content change only either at the rising or falling edge of the enable signal. This enable signal is usually the controlling clock signal. After the rising or falling edge of the clock, the flip-flop content remains constant even if the input changes.

There are basically four main types of latches and flip-flops: SR, D, and JK. The major differences in these flip-flop types are the number of inputs they have and how they change state. For each type, there are also different variations that enhance their operations.

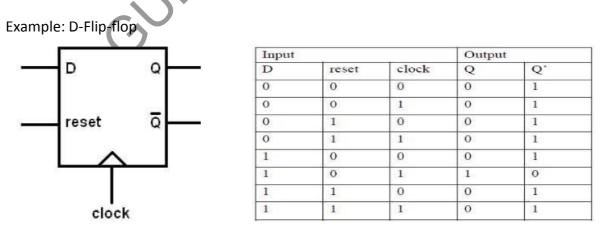


Fig: Block Diagram and truth table of D-Flip Flop

#### Creating a Work space :

• Create a new sub-Directory for the Design and open a terminal from the Sub-Directory.

#### a) Verilog Codes for D-Flip Flop, JK-Flip Flop and SR-Flip Flop.

```
Source code for D-Flip Flop :
`timescale 1ns/1ps
module DFF( Q, Qbar, D, Clk, Reset);
output reg Q;
output Qbar;
input D, Clk, Reset;
always @(posedge Clk)
begin
if (Reset == 1'b1)
                          //If at reset
Q <= 1'b0;
Else
Q <= D;
end
assign Qbar = \simQ;
endmodule
```

Test bench :
`timescale 1ns/1ps
module DFF_test;
reg clk, reset, D;
wire q, qbar;
initial
begin
clk=0;
reset=1; #20;
reset=0;
end
initial
begin
D=0; #100;
D=1; #100;
D=0;
end
dff uut(Q, Qbar, D,clk, reset);
always #5 clk=~clk; // Inverting clk every 5ns
Initial
#1400 \$finish; // Finishing Simulation at t=1400ns
endmodule
Wave Forms :
Baseline ▼ = 0       Image: Cursor-Baseline ▼ = 1,400,000ps         Baseline = 0
Name 🗢 Cursor 🗸 0  20,000ps  40,000ps  60,000ps  80,000ps  100,000ps  120,000ps  140,000ps  160,000ps

```
Source code for D-Latch :
`timescale 1ns/1ps
module Dlatch (Q, Qbar, D, en, Reset);
output reg Q;
output Qbar;
input D, en, Reset;
always @(en or Reset or D)
begin
if (Reset == 1)
                         //If at reset
Q <= 1'b0;
else
 if (en)
 Q <= D;
end
assign Qbar = ~Q;
endmodule
Test bench :
```

`timescale 1ns/1ps module Dlatch\_test; reg en, reset, D; wire Q, Qbar; initial begin en=0;

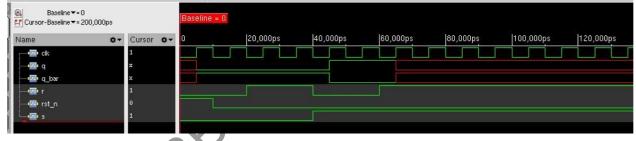
reset=1; #20;	
en=1; #50;	
reset=0;	
end	
initial	
begin	
D=0; #10;	
D=1; #100;	
D=0;	
end	
Dlatch uut (Q, Qbar, D, en, reset); endmodule	
enamodule	$\langle \rangle^{*}$
Wave Forms :	
QL         Baseline ▼= 0         Baseline = 0           Ert Cursor-Baseline ▼= 76,667ps         Baseline = 0	
Name	TimeA = 76,667ps  40,000ps  50,000ps  60,000ps  70,000ps  80,000ps  30,000ps  100,000ps
o O	
Source code for SR Flip Flop.	
`timescale 1ns/1ps	
module srff (clk, rst_n, s,r, q, q_bar);	
input clk, rst_n;	
input s,r;	
output reg q;	
output q_bar;	
<pre>// always@(posedge clk or negedge rst_n)</pre>	// for asynchronous reset
always@(posedge clk)	
begin	// for synchronous reset
if(rst_n)	
q <= 0;	
else	
begin	
case({s,r})	
2'b00: q <= q; // No change	
2'b01: q <= 1'b0; // reset	
2'b10: q <= 1'b1; // set	
2'b11: q <= 1'bx; // Invalid inputs	
endcase	
end	
end	
assign q_bar = ~q;	
<u>endmodule</u>	
I I	
Test bench :	
`timescale 1ns/1ps	
module srff_test;	
reg clk, rst_n;	
reg s, r;	
wire q, q_bar;	
initial begin	
clk = 0;	
rst_n = 1; #10; rst_n = 0;	
end	

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initial begin s=0; r=0; #20; s=0; r=1; #20; s=1; r=0; #20; s=1; r=1; end srff uut (clk, rst\_n, s, r, q, q\_bar); always #5 clk = ~clk; initial #1400 \$finish; endmodule



#### Wave Forms :



#### Source Code for SR Latch :

module srlatch (q, qbar, s, r, en, rst); output reg q; output q; input s, r, en, rst; always @ (en or rst or s or r) begin if (rst) q<=0; else if (en) begin case ({s,r}) 2'b00: q<=q; 2'b01: q<=1'b0; 2'b10: q<=1'b1; 2'b11: q<=1'bx; endcase end end assign qbar=~q; endmodule Test bench : `timescale 1ns/1ps module srlatch\_test; reg en, rst; reg s, r; wire q, qbar; initial begin en=0; rst=1; #10; en=1; rst=0; #10;

rst = 0;

end initial begin s=0; r=0; #20; s=0; r=1; #20;

s=0; 1=1; #20; s=1; r=0; #20; s=1; r=1; #20; end srlatch uut (q, qbar, s, r, en, rst); initial #1400 \$finish; endmodule



Wave Forms :

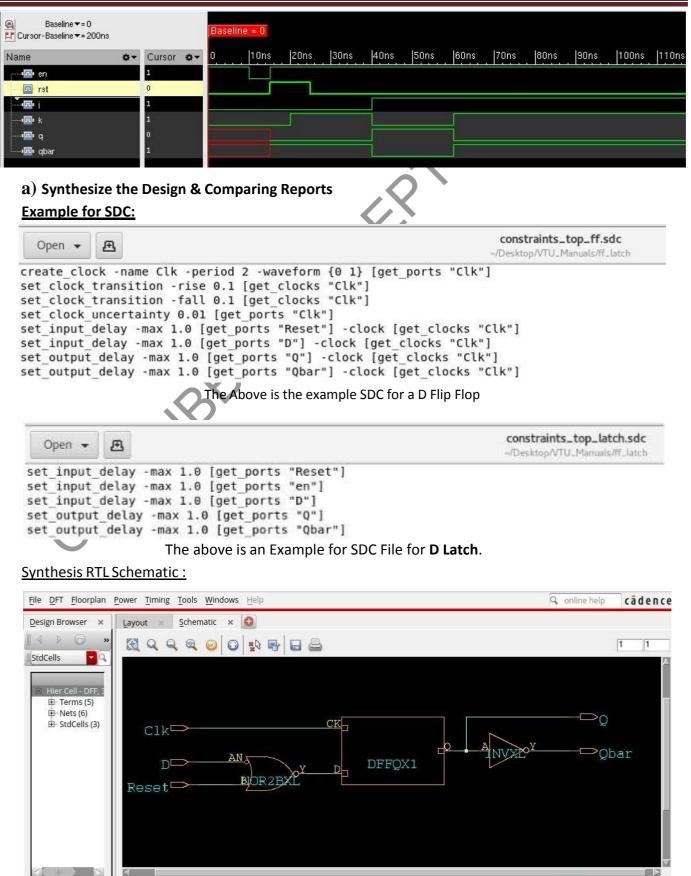
Baseline▼= 0 Inf Cursor-Baseline▼= 200,000ps	Baseline = 0						
Name Ov Cursor Ov	0	20,000ps	40,000ps	60,000ps	80,000ps	100,000ps	12
en 1 							
qbar x							
1 							
1							
Source Code for JK Flip Flop :							
module jkff (clk, rst, J, K, q, ql	bar);						
input J, K, clk, rst; output reg Q;							
output qbar;							
always @(posedge clk)							
begin							
if (rst)							
q<=0;							
else							
begin case ({j,k})							
2'b00: q<= q;							
2'b01: q<= 1'b0;							
2'b10: q<= 1'b1;							
2'b11: q<= ~q;							
endcase							
end							
end assign qbar= ~q;							
endmodule							
<u>Test bench :</u>							
Module jkff_test;							
reg clk, rst, j, k; wire q, qbar;							
initial begin							
clk =0; rst =1; #10;							
rst =0;							
end							
initial begin							
j=0; k=0; #20;							
j=0; k=1; #20;							
j=1; k=0; #20;							

j=1; k=1; #20; end jkff uut (clk, rst, j, k, q, qbar); always #5 clk =~clk; endmodule

#### Wave Forms :



#### VLSI LAB 21ECL66



design:DFF

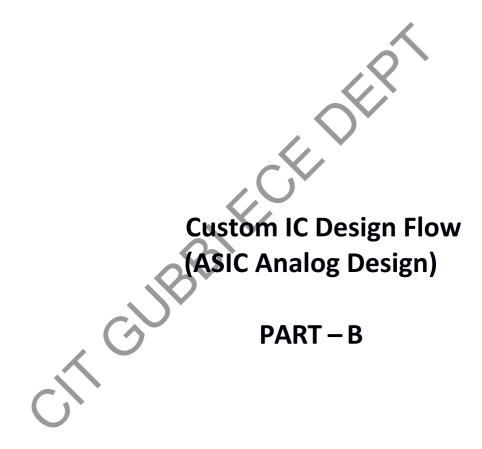
DFF 1

Fig: Schematic of D-Flip Flop

#### <u> Note :-</u>

- 1. You can tabulate Area, Power and Timing Constraints using any of the SDC Constraints as instructed.
- 2. Make sure, during synthesis the Report File Names are changed sothat the latest reports do not overwrite the earlier ones.

auto update: 2000



# Objective:

(a) Capture the Schematic of a CMOS Inverter with Load Capacitance of 0.1 pF and set the Widths of Inverter with

LAB – 01: CMOS INVERTER

(i)  $W_N = W_P$ 

(ii)  $W_N = 2 W_P$ 

(iii)  $W_N = W_P / 2$ 

and Length at selected Technology. Carry out the following:

- 1. Set the Input Signal to a pulse with Rise Time, Fall Time of 1 ps and Pulse Width of 10 ns, Time Period of 20 ns and plot the input voltage and output voltage of the designed Inverter
- 2. From the Simulation Results, compute  $tp_{HL}$ ,  $tp_{LH}$  and  $t_{PD}$  for all the three geometrical settings of Width
- 3. Tabulate the results of delay and find the best geometry for minimum delay for CMOS Inverter

#### Solution:

## 

For the CMOS Inverter circuit, PMOS and NMOS transistors are required. The parameters for the devices as given in the requirement are considered as in Table – 1, Table – 2 and Table – 3. Table – 1: Length and Width of NMOS and PMOS Transistors for the condition WN = WP

Library Name	Cell Name	Comments / Properties	
gpdk180	Nmos	Width, W <sub>N</sub> = 850 n	
		Length, L = 180 n	
gpdk180	Pmos	Width, W <sub>P</sub> = 850 n	
		Length, L = 180 n	

Table – 2: Length and Width of NMOS and PMOS Transistors for the conditionWN = 2 \* WP

Library Name	Cell Name	Comments / Properties
gpdk180	Nmos	Width <i>,</i> WN = 850 n
		Length, L = 180 n
gpdk180	Pmos	Width, $W_P = 1.7 u$
		Length, L = 180 n

Table – 3: Length and Width of NMOS and PMOS Transistors for the condition WN = WP/2

Library Name	Cell Name	Comments / Properties	
gpdk180	Nmos	Width, $W_N = 850 n$	
		Length, L = 180 n	
gpdk180	Pmos	Width, $W_P = 425 n$	
		Length, L = 180 n	

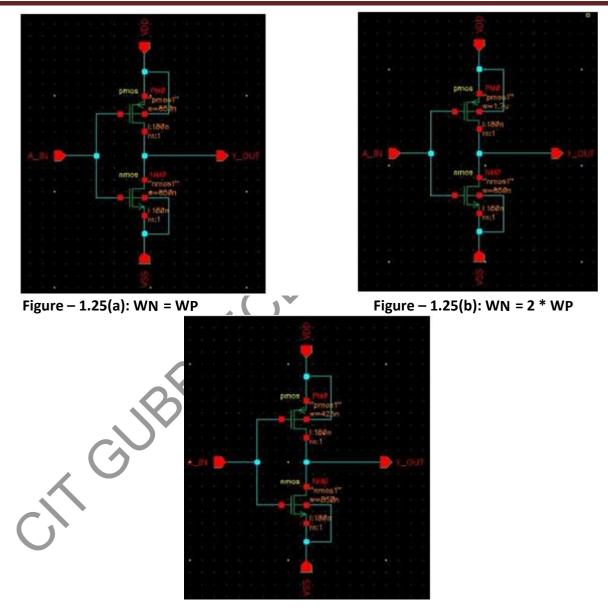


Figure – 1.25(c): WN = WP / 2

**SYMBOL CREATION:** 

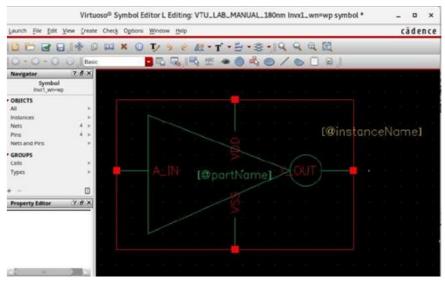
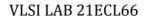


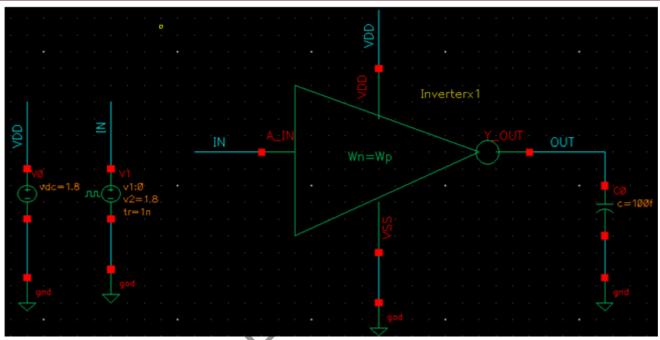
Figure – 1.35: Customized Symbol of an Inverter

#### (1) TEST CIRCUIT FOR SIMULATION:

The complete circuit after instantiating all the devices and interconnections is shown in Figure – 1.42.

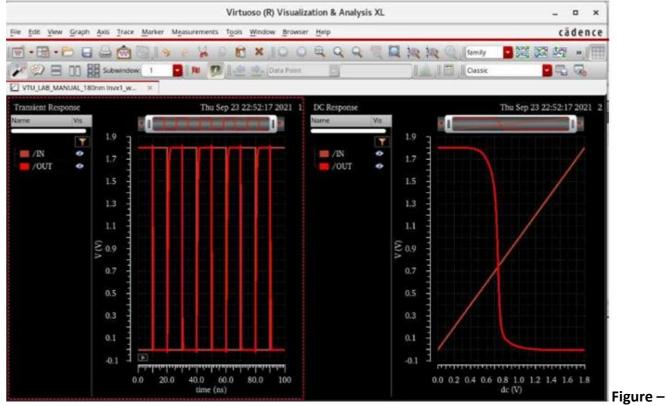


2023-2024



# Figure -1.42: Complete Test Schematic

FUNCTIONAL SIMULATION WITH SPECTRE:



#### 1.70: Simulated waveforms

The Input and Output Signals can be split up by selecting "Graph —>Split All Strips" as in Figure – 1.71.

#### (1) CALCULATION OF tpHL, tpLH AND tPD:

To calculate the Propagation Delay  $(t_{PD})$ , the formula used is

$$(tpLH + tpHL)$$
$$tPD = \frac{2}{2}$$

where,  $tp_{LH}$  —> Low – High Propagation Delay and  $tp_{HL}$  —> High – Low Propagation Delay.

To calculate  $tp_{LH}$  and  $tp_{HL}$  use the Calculator option from the "Virtuoso (R) Visualization and Analysis" window. So, select "Tools —> Calculator" or click on the icon as shown in Figure – 1.78.

#### **TABULATED VALUES OF DELAY:** (2)

The results of  $tp_{HL}$ ,  $tp_{LH}$  and  $t_{PD}$  for all the required geometrical settings are tabulated belowin Table – 5.

Width Settings	MOSFET	Width	tpLH	tpHL	tpd
Wp =Wn	PMOS	850n	3.233E-10	7 040E 10	5.141E-10
	NMOS	850n	5.255E-10	7.049E-10	5.141E-10
Wn =2Wp	PMOS	850n	3.337E-10	4.700E-10	4.019E-10
	NMOS	1.7u	5.55/E-10		
Wn = Wp/2	PMOS	425n	1.141E-09	3.154E-10	7.282E-10
	NMOS	850n	1.141E-09	3.134E-10	7.202E-10

Table -5: Values of tp<sub>HL</sub>, tp<sub>LH</sub> and t<sub>PD</sub> for different geometries

(a) Layout of CMOS Inverter with 
$$\frac{W_p}{W_p} = \frac{40}{20}$$

#### **Objective:**

**Objective:** To draw the Layout of CMOS Inverter with  $\frac{W_p}{W_p} = \frac{40}{20}$  using optimum Layout Methods. Verify for DRC and LVS, extract the Parasitics and perform the Post-Layout Simulations, compare the results with Pre-Layout Simulations and record the observations.

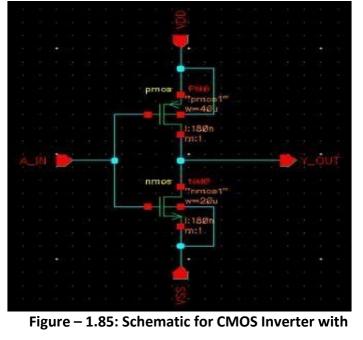
## **SCHEMATIC CAPTURE:**

Create a New Library, Create a Cellview and instantiate the required devices through "Create Instance" option. The parameter for PMOS and NMOS Transistors are listed in Table - 6 shown below.

Library Name	Cell Name	Comments / Properties		
and 1.1.00	Nmoc	Width, $W_N = 20 u$		
gpdk180	Nmos	Length, L = 180 n		
gpdk180	Dmoc	Width, $W_P = 40 u$		
	Pmos	Length, L = 180 n		

Table – 6: Parameters for NMOS and PMOS Transistors

Follow the techniques demonstrated in Lab – 01 to complete the Schematic. The completed CMOS Inverter circuit is shown in Figure – 1.85.



20

The symbol for the CMOS Inverter is shown in Figure – 1.86.

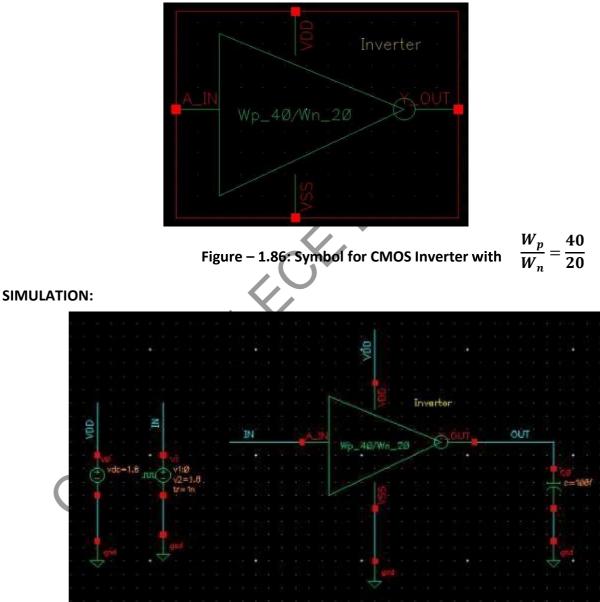


Figure – 1.88: Updated ADE L window

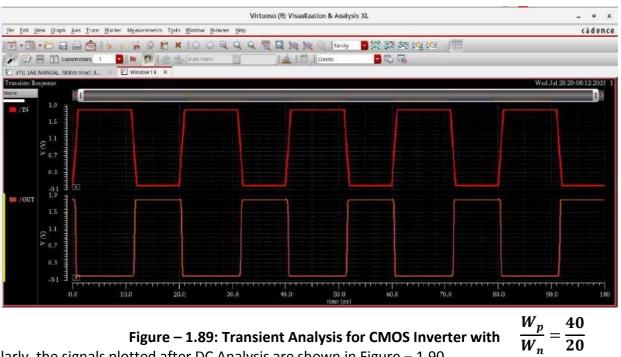
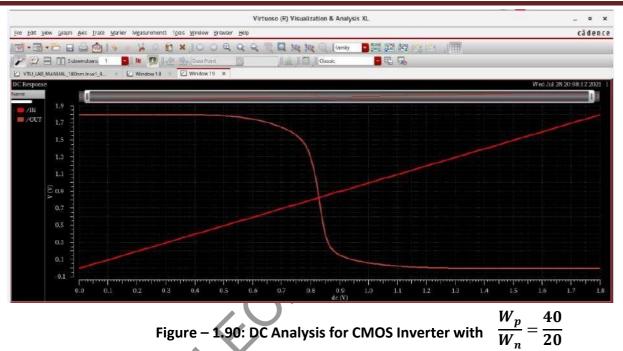


Figure – 1.89: Transient Analysis for CMOS Inverter with Similarly, the signals plotted after DC Analysis are shown in Figure – 1.90.



VALUES OF  $tp_{HL}$ ,  $tp_{LH}$  AND  $t_{PD}$ :

Obtain the values of  $tp_{HL}$ ,  $tp_{LH}$  and  $t_{PD}$  by referring to "CALCULATION OF tpHL, tpLHAND tPD" in the previous section. The values are tabulated as shown in Table – 7

	$W_p$	40
Table – 7: Values <i>tp<sub>HL</sub>, tp<sub>LH</sub></i> AND <i>for CMOS Inverter with</i>	$\overline{W_n}$	20

$\boldsymbol{\mathcal{C}}$	MOSFET	Length	Width	tpLH	tpHL	tpd
	PMOS	180n	40u	1 2295 10	3.550E-11	7.920E-11
	NMOS	180n	20u	1.226E-10	5.550E-11	7.920E-11

# LAB – 02: 2 – INPUT CMOS NAND GATE

# **Objective:**

- (a) Capture the Schematic of a 2 input CMOS NAND Gate having similar delay as that of CMOS Inverter computed in Lab 01. Verify the functionality of the NAND Gate and also find out the delay for all the four possible combinations of input vectors. Tabulate the results. Increase the drive strength to 2X and 4X and tabulate the results.
- (**b**) Draw the layout of NAND with  $\frac{W_p}{W_n} = \frac{40}{20}$  use optimum layout methods. Verify DRC

and LVS, extract the parasitics and perform the post layout simulation, compare theresults with pre layout simulations. Record the observations.

#### Solution – (a): SCHEMATIC CAPTURE:

Following the techniques demonstrated in Lab – 01, Create a New Library using the option "File —> New —> Library", create a New Cell View upon selecting the newly created library using the option "File —> New —> Cell View" and instantiate the required devices using the "Create —> Instance" option.

The device parameters are listed in Table – 9.

#### Table – 9: Width and Length of NMOS and PMOS Transistors for CMOS NAND Gate

Library Name	Cell Name	Comments / Properties	
gpdk180	Nmos	Width, $W_N = 1.7 u$	
		Length, L = 180 n	
gpdk180	Pmos	Width, W <sub>P</sub> = 1.275 u	
C		Length, L = 180 n	

Similarly, the device parameters for the 2 – input CMOS NAND Gate with drive strength 2 and drive strength 4 are listed in Table – 10 and Table – 11.

# Table – 10: Width and Length of NMOS and PMOS Transistors for CMOS NAND Gate with Drive Strength "2"

Library Name	Cell Name	Comments / Properties	
gpdk180	Nmos	Width, $W_N = 3.4 u$	
		Length, L = 180 n	
gpdk180	Pmos	Width, W <sub>P</sub> = 2.55 u	
		Length, L = 180 n	

Table – 11: Width and Length of NMOS and PMOS Transistors for CMOS NAND Gate with Drive Strength "4"

Library Name	Cell Name	Comments / Properties
gpdk180	Nmos	Width, $W_N = 6.8 u$
		Length, L = 180 n
gpdk180	Pmos	Width, $W_P = 5.1 u$
		Length, L = 180 n

The completed Schematic for all the three dimensions are shown in Figure -2.1, Figure -2.2 and Figure -2.3.

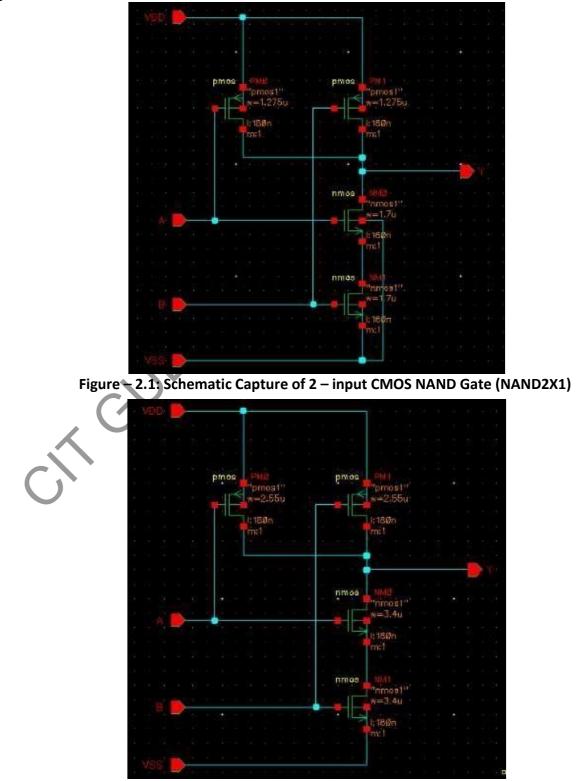
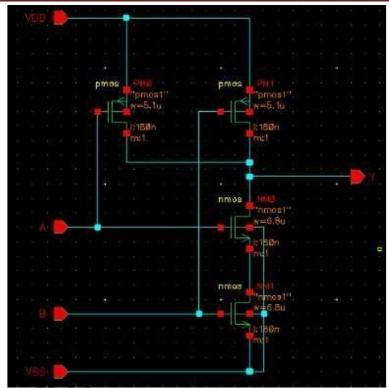


Figure – 2.2: Schematic Capture of 2 – input CMOS NAND Gate with drive strength 2(NAND2X2)



**Figure – 2.3: Schematic Capture of 2 – input CMOS NAND Gate with drive strength 2(NAND2X4)** The symbol for the CMOS NAND Gate is shown in Figure – 2.4.

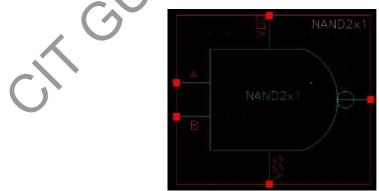


Figure – 2.4: Symbol of 2 – input NAND Gate

FUNCTIONAL SIMULATION:

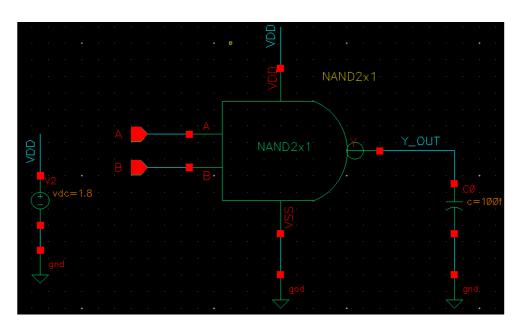


Figure – 2.5: Test Schematic for 2 – input CMOS NAND Gate

The Simulated waveforms can be seen as shown in Figure – 2.9.



#### Figure – 2.9: Transient Analysis of 2 – input CMOS NAND Gate

The delay values are obtained using the "**Calculator**" option as demonstrated in Lab -01. Theresults are tabulated as shown in Table -12.

Table – 12: Values of Delay for 2 – input CMOS NAND2X1,	NAND2X2 and NAND 2X4
---	----------------------

NAND Type	MOSFET	Length	Width	tpLH	tpHL	tpd
NAND2X1	PMOS	180n	1.5 * 850n = 1.275u	3.720E-10	3.340E-10	3.530E-10
	NMOS	1801	2 * 850n = 1.7u	5.720E-10	5.540E-10	5.550E-10
NAND2X2	PMOS	180n	1.5 * 850n * 2 = 2.55u	2.610E-10	2.200E-10	2.400E-10
	NMOS	1801	2 * 850n * 2 = 3.4u	2.010E-10	2.200E-10	2.400E-10
NAND2X4	PMOS	180n	1.5 * 850n * 4 = 5.1u	1.900E-10	1.650E-10	1.780E-10
	NMOS	1801	2 * 850n * 4 = 6.8u	1.900E-10	1.050E-10	1.780E-10

Solution – (b):

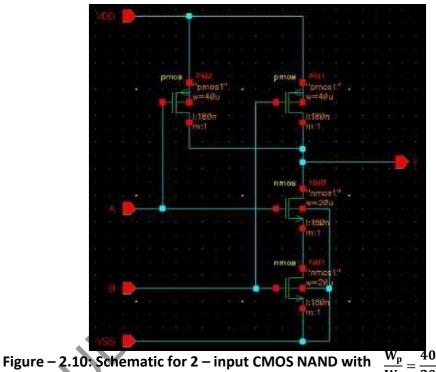
#### SCHEMATIC CAPTURE:

Following the techniques demonstrated in Lab - 01, Create a New Library, a New Cell View and instantiate the devices as per the Schematic of 2 - input CMOS NAND Gate. The device parameters for the NMOS and PMOS Transistors are listed in Table - 13.

# Table – 13: Device parameters for 2 – input CMOS NAND Gate with $\frac{W_p}{W_n} = \frac{40}{20}$

Library Name	Cell Name	Comments / Properties
gpdk180	Nmos	Width, W <sub>N</sub> = 20 u Length, L = 180 n
gpdk180	Pmos	Width, W <sub>P</sub> = 40 u Length, L = 180 n

The Schematic as per the dimensions of NMOS and PMOS transistors listed above is shown in Figure – 2.10.



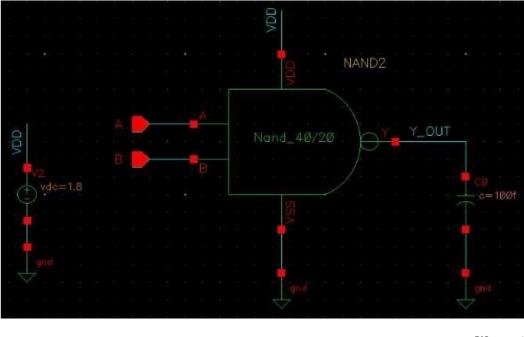
Symbol for the Schematic in Figure – 2.10 is shown in Figure – 2.11.  $\frac{1}{W_n} = \frac{1}{20}$ 

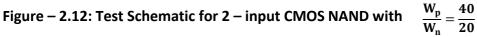


Figure – 2.11: Symbol for 2 – input CMOS NAND with  $\frac{W_p}{W_n} = \frac{40}{20}$ 

#### FUNCTIONAL SIMULATION:

The Test Schematic for the functionality check of the 2 – input CMOS NAND Gate is shownin Figure – 2.12.





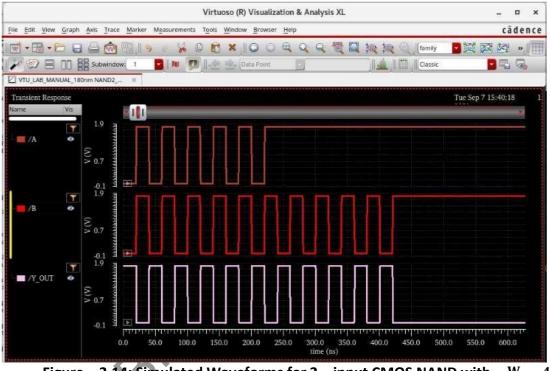


Figure – 2.14: Simulated Waveforms for 2 – input CMOS NAND with  $\frac{W_p}{W_n} = \frac{40}{20}$ 

The values of delay elements are tabulated in Table – 14.

Table – 14: Delay Elements for 2 – input CMOS NAND Gate with  $\frac{W_p}{W_n} = \frac{40}{20}$ (Pre Layout *Simulation*)

MOSFET	Length	Width	tpLH	tpHL	tpd
PMOS	180n	40u	3.64E-11	1.55E-10	9.57E-11
NMOS	180n	20u	5.04E-11	1.55E-10	9.3/E-11

LAYOUT:

Follow the techniques demonstrated in Lab - 01 to open the Layout Editor, import the devices from the Schematic, place the devices as per the requirement and complete the routing. The completed layout can be seen as shown in Figure - 2.15.

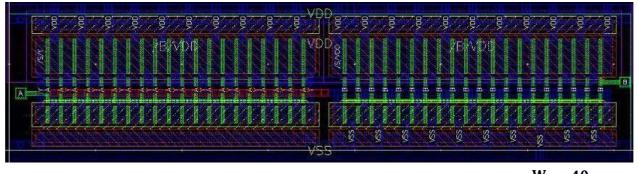


Figure – 2.15: Layout for 2 – input CMOS NAND Gate with  $\frac{W_p}{W_n} = \frac{40}{20}$ 

DRC:

To check for the DRC violations, browse the "assura\_tech.lib" file, select "Assura —> Run DRC", verify the Layout Design Source, mention a "Run Name", select "Technology —> gpdk180" and click on "OK" as demonstrated in Lab – 01.

#### LVS:

To check for the LVS violations, select "Assura —> Run LVS", verify the Schematic Design Source and the Layout Design Source, mention a "Run Name", select "Technology —> gpdk180" and click on "OK" as demonstrated in Lab – 01.

#### QRC:

To extract the Parasitics, select "Assura —> Quantus", select "Technology —> gpdk180", "Output —> Extracted View" from the "Setup" option, select "Extraction Type —> RC" and "Ref Node —> VSS" from the "Extraction" and click on "OK" as demonstrated in Lab – 01. The result can be checked from the Library Manager.

#### **BACKANNOTATION:**

Import the parasitics into the Test Schematic and re-run the simulation to check their impact by calculating the delay elements as demonstrated in Lab – 01.

The values of delay are shown in Table – 15.

	W <sub>p</sub> 40
Table – 15: Delay Elements for 2 – input CMOS NAND Gate with	$\frac{P}{W} = \frac{1}{20}$ (Post Layout <i>Simulation</i> )
	$vv_n 20$

MOSFET	Length	Width	tpLH	tpHL	tpd
PMOS	180n	40u	3.64E-11	1.55E-10	9.57E-11
NMOS	180n	20u	5.04E-11	1.55E-10	9.37E-11
C/	G				

#### LAB – 03: COMMON SOURCE AMPLIFIER WITH PMOS CURRENT MIRROR LOAD Objective:

- (a) Capture the Schematic of a Common Source Amplifier with PMOS Current Mirror Load and find its Transient Response and AC Response. Measure the UGB and Amplification Factor by varying transistor geometries, study the impact of variation in width to UGB.
- (b) Draw the layout of Common Source Amplifier, use optimum layout methods. Verify DRC and LVS, extract the parasitics and perform the post layout simulation, compare the results with pre layout simulations. Record the observations.

#### Solution – (a):

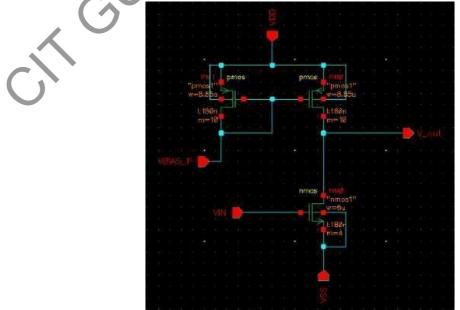
#### SCHEMATICCAPTURE:

Following the techniques demonstrated in Lab – 01, Create a New Library using the option" File  $\rightarrow$ New  $\rightarrow$  Library", create a New Cell View upon selecting the newly created library using the option "File  $\rightarrow$  New  $\rightarrow$  Cell View" and instantiate the required devices using the "Create  $\rightarrow$  Instance" option. The device parameters are listed in Table–16.

Table –16: Width and Length of NMOS and PMOS Transistors

LibraryName	CellName	Comments/Properties
gpdk180	Nmos	Width,W <sub>N</sub> =6 u
0		Length, L=180 n
gpdk180	Pmos	Width, W <sub>P</sub> = 8.85u
		Length, L=180 n

The completed Schematic is shown in Figure–3.1.



*Figure – 3.1: Schematic of Common Source Amplifier with PMOS Current Mirror Load* The symbol for the Common Source Amplifier with PMOS Current Mirror Load is shown in Figure – 3.2.

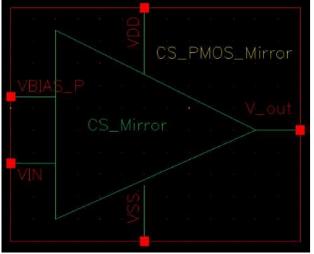
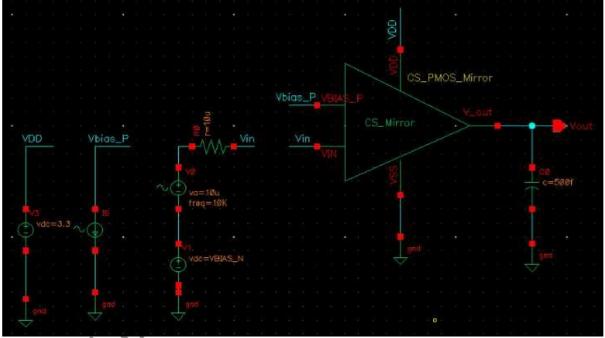


Figure – 3.2: Symbol of Common Source Amplifier with PMOS Current Mirror Load

#### FUNCTIONAL SIMULATION:

Using the symbol created, build the Test Schematic. Create a New Cell View, instantiate the symbol of Common Source Amplifier with PMOS Current Mirror Load, DC Voltage Source, Current Source, AC Voltage Source, Capacitance, Resistance and Ground, connect the using wires



**Figure – 3.3: Test Schematic for 2 – input CMOS NAND Gate** maining devices are shown in Table – 17.

Library Name	Cell Name	Comments / Properties
analogLib	vdc	DC voltage = 3.3 V (VDD)
analogLib	vdc	DC voltage = VBIAS_N V (Vin)
analogLib	isin	DC current = 100u A (Vbias_P)
analogLib	vsin	AC Magnitude = 1 V, Amplitude = 10u V, Frequency = 10K Hz (Vin)
analogLib	сар	Capacitance = 500f F
analogLib	res	Resistance = 10u Ohms
analogLib	gnd	

Table – 17: Parameters for the devices used in Test Schematic

The Simulated waveforms can be seen as shown in Figure – 3.5 and Figure – 3.6.

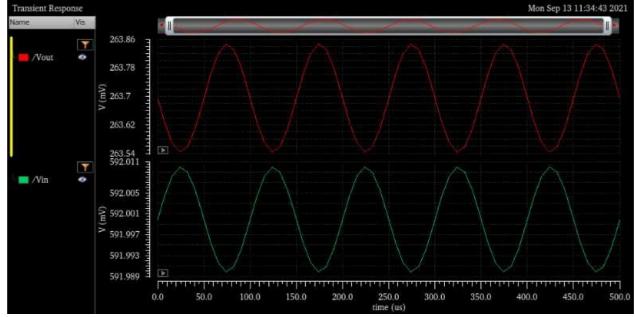


Figure – 3.5: Transient Analysis

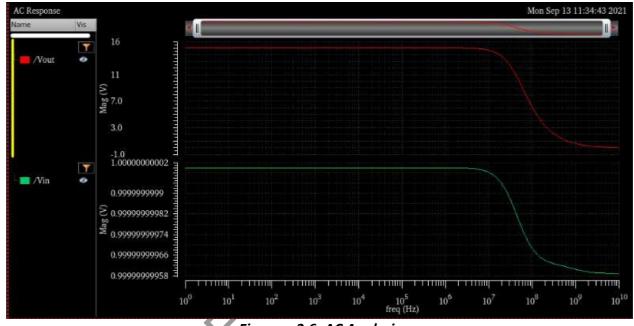


Figure – 3.6: AC Analysis

To measure the Gain and Unity Gain Bandwidth, go back to the ADE L window, select "**Results**  $\rightarrow$  **Direct Plot**  $\rightarrow$  **AC Magnitude & Phase**" as shown in Figure – 3.7.

The Test Schematic window pops up, select the output net as shown in Figure – 3.8 and click on "Esc" key on the keyboard.

The waveform can be seen as shown in Figure – 3.9. The marker placed on the low frequency part of the response gives the DC Gain, use the bind key " $\mathbf{M}$ " to place the marker.

Place a horizontal cursor at "**0** dB" and the crossing frequency gives the Unity Gain Bandwidth (UGB) as shown in Figure 3.9.

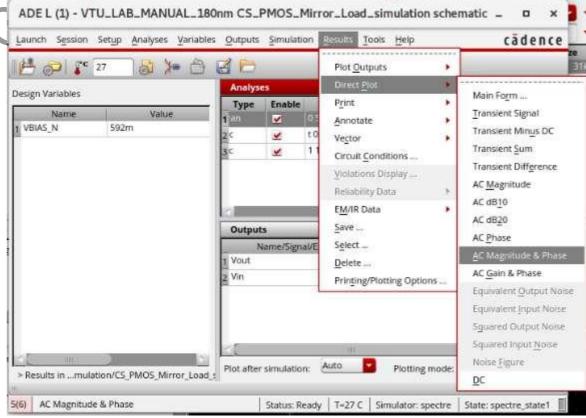


Figure – 3.7: Results  $\rightarrow$  Direct Plot  $\rightarrow$  AC Magnitude & Phase

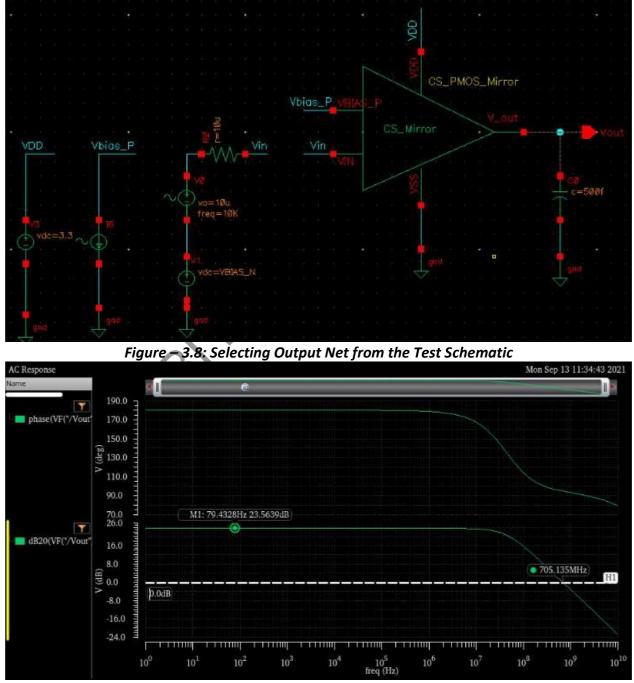


Figure – 3.9: Gain and Phase plot

#### Solution – (b): LAYOUT:

Follow the techniques demonstrated in Lab - 01 to open the Layout Editor, import the devices from the Schematic, place the devices as per the requirement and complete the routing. The completed layout can be seen as shown in Figure - 3.10.

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Figure – 3.10: Layout for Common Source Amplifier with PMOS Current Mirror Load

#### DRC:

To check for the DRC violations, browse the "assura\_tech.lib" file, select "Assura  $\rightarrow$  Run DRC", verify the Layout Design Source, mention a "Run Name", select "Technology  $\rightarrow$  gpdk180" and click on "OK" as demonstrated in Lab – 01.

#### LVS:

To check for the LVS violations, select "Assura  $\rightarrow$  Run LVS", verify the Schematic Design Source and the Layout Design Source, mention a "Run Name", select "Technology  $\rightarrow$  gpdk180" and click on "OK" as demonstrated in Lab – 01.

#### QRC:

To extract the Parasitics, select "Assura  $\rightarrow$  Quantus", select "Technology  $\rightarrow$  gpdk180", "Output  $\rightarrow$  Extracted View" from the "Setup" option, select "Extraction Type  $\rightarrow$  RC" and "Ref Node  $\rightarrow$  VSS" from the "Extraction" and click on "OK" as demonstrated in Lab – 01. The result can be checked from the Library Manager.

#### **BACKANNOTATION:**

Import the parasitics into the Test Schematic and re-run the simulation to check their impact by calculating the delay elements as demonstrated in Lab – 01.

# LAB – 04: 2 – STAGE OPERATIONAL AMPLIFIER

#### **Objective:**

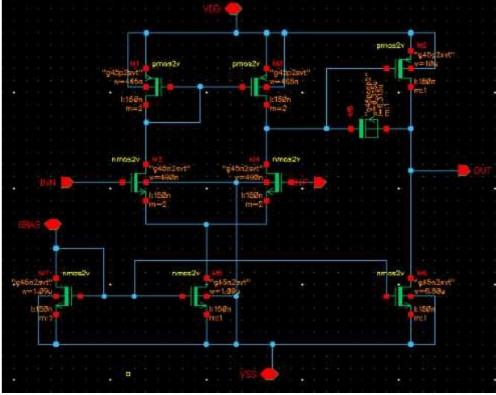
- a) Capture the Schematic of a 2 Stage Operational Amplifier and measure the following:
  - 1. UGB
  - 2. dB Bandwidth
  - 3. Gain Margin and Phase Margin with and without coupling capacitance
  - 4. Use the Op-Amp in the Inverting and Non-Inverting configuration and verify its functionality
  - 5. Study the UGB, 3 dB Bandwidth, Gain and Power Requirement in Op-Amp by varying the stage wise transistor geometries and record the observations
- b) Draw the layout of 2 stage Operational Amplifier with the maximum transistor width set to 300 (in 180 / 90/ 45n m Technology), choose appropriate transistor geometries as per the results obtained in 4(a). Use optimum layout methods. Verify DRC and LVS, extract the parasitics and perform the post layout simulation, compare the results with pre layout simulations. Record the observations.

#### Solution – (a): SCHEMATIC CAPTURE:

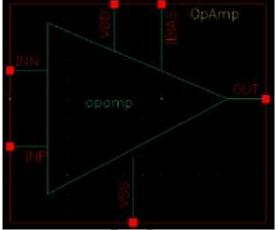
Library Name	Transistor	Cell Name	Comments / Properties
gpdk045	M0, M1	pmos2v	Width, W = 465 n Length, L = 150 n
gpdk045	M3, M4	nmos2v	Width, W = 490 n Length, L = 150 n
gpdk045	M5, M7	nmos2v	Width, W = 1.09 u Length, L = 150 n
gpdk045	M2	pmos2v	Width, W = 10 u Length, L = 150 n
gpdk045	M6	nmos2v	Width, W = 6.88 u Length, L = 150 n
gpdk045	M8	pmoscap2v	Calculated Parameter = Capacitance
Sharo+2	1010	μποστάμεν	Capacitance = 250.043 f

#### Table – 18: Device Parameters for 2 – Stage Operational Amplifier

The completed Schematic as per the dimensions mentioned in Table – 18 is shown in Figure – 4.2.



**Figure – 4.2: Schematic of 2 – Stage Operational Amplifier** The Symbol created according to the Techniques demonstrated in Lab – 01 is shown in Figure – 4.3.



*Figure – 4.3: Symbol for 2 – Stage Operational Amplifier* FUNCTIONAL SIMULATION USING ADE EXPLORER AND ASSEMBLER:

#### Table – 19: Device Parameters for 2 – Stage Operational Amplifier Test Schematic

Library Name	Cell Name	Comments / Properties
analogLib	vdc	DC voltage = vdd V
analogLib	vdc	DC voltag
analogLib	vpulse	Voltage 1 = vdc + 0.3 V, Voltage 2 = vdc - 0.3 V, Period = 10u s, Rise time = 10p s, Fall time = 10p s
analogLib	idc	DC current = ibias A
analogLib	cap	Capacitance = CL F
analogLib	gnd	

The Test Schematic after completion of all the interconnections can be seen as shown in Figure – 4.4.

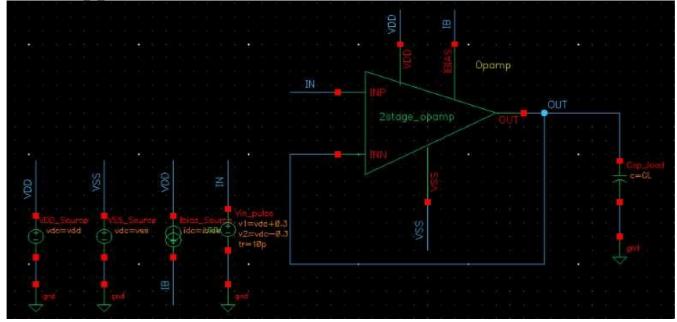


Figure – 4.4: Test Schematic for 2 – Stage Operational Amplifier

The specification that has to be achieved on simulating the design are as follows:

- Slew Rate >= 50 MV/s
- DC Open Loop Gain >= 60 dB (1000 V/V)
- Unity Gain Bandwidth >= 50 MH
- Output Offset <= ± 10 mV
- Settling Time <= 50 ns

The steps to be carried out are listed below:

#### Step – 1:

Select "Launch  $\rightarrow$  ADE Explorer" as shown in Figure – 4.5.

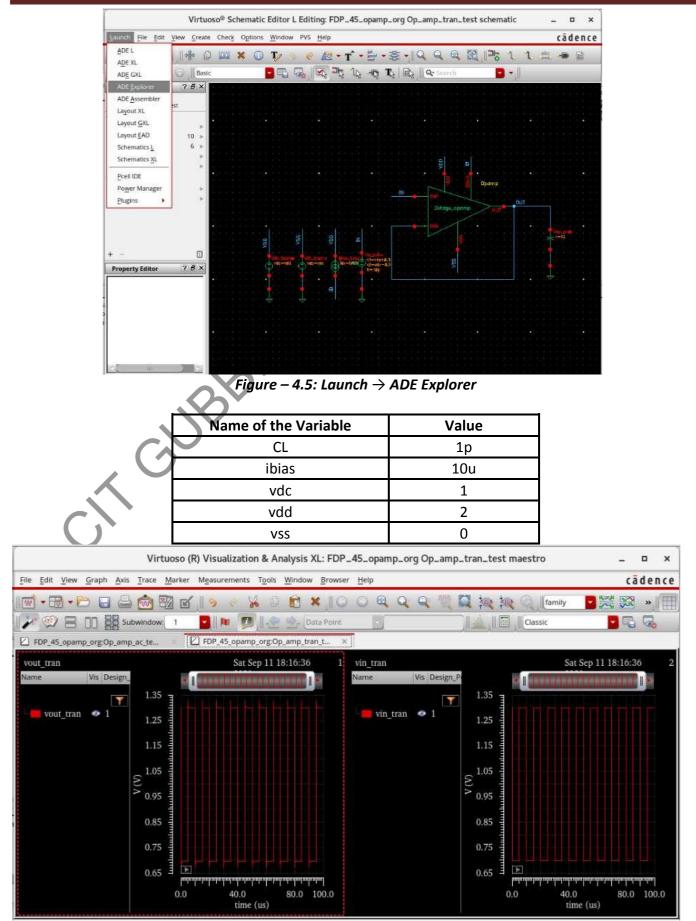


Figure – 4.40: Plotted Waveforms

#### VLSI LAB 21ECL66

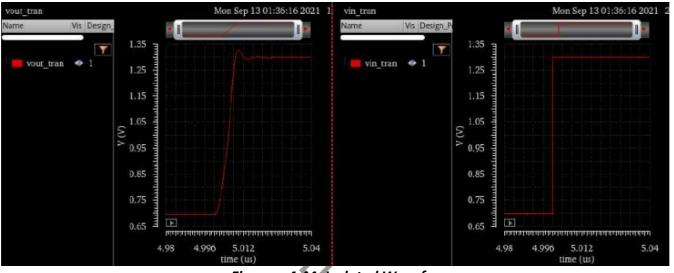
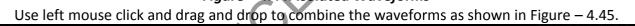
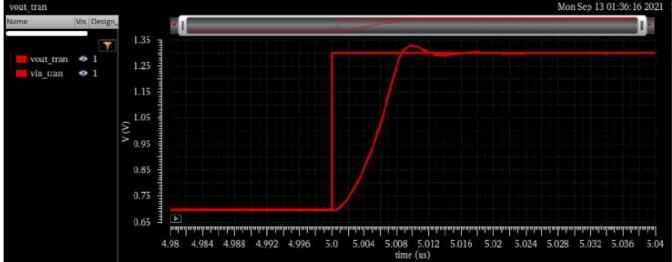
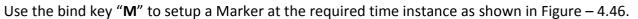


Figure – 4.44: Isolated Waveforms





#### Figure – 4.45: Combined Waveforms



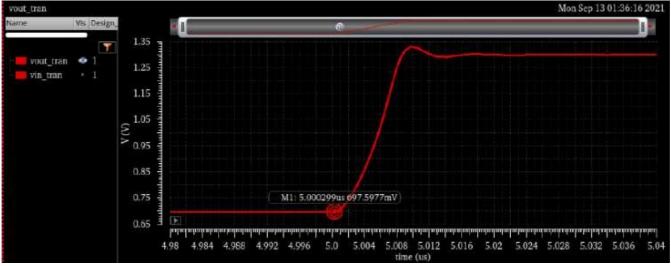


Figure – 4.46: Waveform with Marker

Use the bind key "H" to setup horizontal cursors at **1.294 V** and **1.306 V** as shown in Figure – 4.47.

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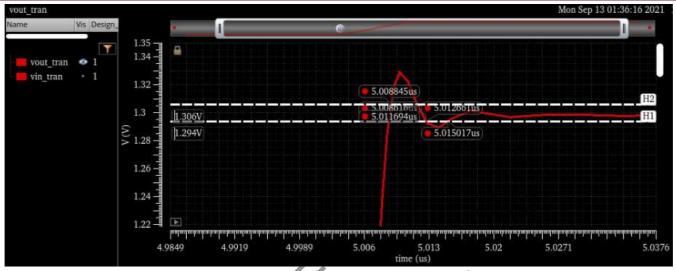
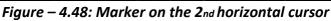


Figure – 4.47: Horizontal cursors at 1.294 V and 1.306 V

Use the zooming options to zoom-in and zoom-out as and when required. Setup a marker on the lower horizontal cursor as shown in Figure -4.48.





The difference between the timing instances gives the **Settling Time** as **12.5n s**. Without closing the waveform window, open the "**maestro**" in the ADE Assembler. For this simulation, the output dc value is 1.298 V and the input dc value is 1.3 V. The difference gives the **DC Offset (1.298 V – 1.3 V = 2m V)**. From the AC Analysis curve, set the marker on the low frequency portion of the signal as shown in Figure – 4.49.

The marker reading gives the **DC Open Loop Gain** which is **50.98 dB**.

Setup a horizontal cursor at **0 dB** as shown in Figure – 4.50. The point of intersection of the cursor with the AC Analysis curve gives the Unity Gain Bandwidth.

The Unity Gain Bandwidth is measured as 84.51M Hz.

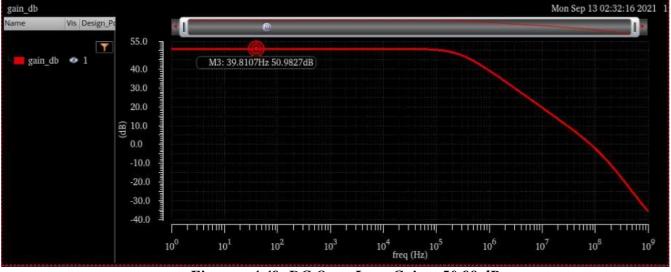


Figure – 4.49: DC Open Loop Gain – 50.98 dB

#### VLSI LAB 21ECL66

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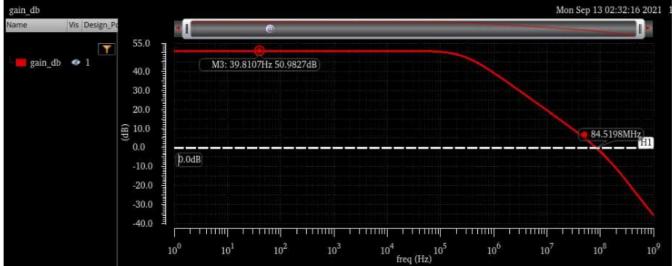


Figure – 4.50: Unity Gain Bandwidth – 84.51M Hz

#### GAIN MARGIN AND PHASE MARGIN:

The Schematic for measuring the Gain Margin and Phase Margin is shown in Figure – 4.68.

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Figure – 4.68: Schematic for Gain Margin and Phase Margin measurement

The "iprobe" (available in "analogLib") acts as a signal source for the stability analysis. Create a Test Copy for the Stability Analysis as shown in Figure – 4.69.

#### LAYOUT:

Follow the techniques demonstrated in Lab – 01 to open the Layout Editor, import the devices from the Schematic, place the devices as per the requirement and complete the routing. The completed layout can be seen as shown in Figure – 4.76.

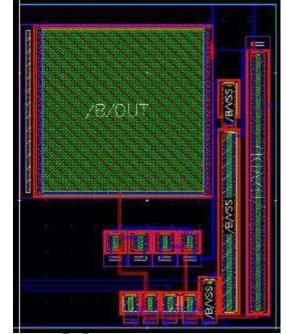


Figure – 4.76: Layout for 2 – Stage Operational Amplifier

#### DRC:

To check for the DRC violations, browse the "assura\_tech.lib" file, select "Assura  $\rightarrow$  Run DRC", verify the Layout Design Source, mention a "Run Name", select "Technology  $\rightarrow$  gpdk045" and click on "OK" as demonstrated in Lab – 01.

## LVS:

To check for the LVS violations, select "Assura  $\rightarrow$  Run LVS", verify the Schematic Design Source and the Layout Design Source, mention a "Run Name", select "Technology  $\rightarrow$  gpdk045" and click on "OK" as demonstrated in Lab – 01.

#### QRC:

To extract the Parasitics, select "Assura  $\rightarrow$  Quantus", select "Technology  $\rightarrow$  gpdk180", "Output  $\rightarrow$  Extracted View" from the "Setup" option, select "Extraction Type  $\rightarrow$  RC" and "Ref Node  $\rightarrow$  VSS" from the "Extraction" and click on "OK" as demonstrated in Lab – 01. The result can be checked from the Library Manager.

#### **BACKANNOTATION:**

Import the parasitics into the Test Schematic and re-run the simulation to check their impact by calculating the delay elements as demonstrated in Lab - 01.

# **Demonstration Experiments**

# Lab 9: UART

<u>Aim:</u> Write a verilog code for UART and carry out the following:

- To Verify the Functionality using test Bench
- Synthesize Design using constraints
- Tabulate Reports using various Constraints
- Identify Critical Path and calculate Max Operating Frequency

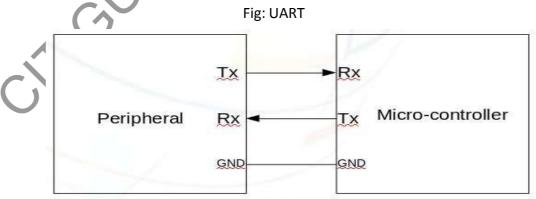
### **Tool Required:**

- Functional Simulation: Incisive Simulator (ncvlog, ncelab, ncsim)
- Synthesis: Genus

# Design Information and Bock Diagram:

The **UART** is "Universal Asynchronous Receiver/Transmitter", and it is an inbuilt IC within a micro-controller but not like a communication protocol (I2C & SPI). The main function of UART is to serial data communication. In UART, the communication between two devices can be done in two ways namely serial data communication and parallel data communication.

The transmitter section includes three blocks namely transmit hold register, shift register and also control logic. Likewise, the receiver section includes a receive hold register, shift register, and control logic. These two sections are commonly provided by a baud-rate-generator. This generator is used for generating the speed when the transmitter section & receiver section has to transmit or receive the data.



**UART** Communication

Creating a Workspace :

• Create a new sub-Directory for the Design and open a terminal from the Sub-Directory.

# a) Functional Verification using Test Bench

#### Source Code – Transmitter :

// This code contains the UART Transmitter. This transmitter is able

// to transmit 8 bits of serial data, one start bit, one stop bit,

// and no parity bit. When transmit is complete o\_Tx\_done will be

// driven high for one clock cycle.

// Set Parameter CLKS\_PER\_BIT as follows:

// CLKS\_PER\_BIT = (Frequency of i\_Clock)/(Frequency of UART)

// Example: 25 MHz Clock, 115200 baud UART

// (2500000)/(115200) = 217

```
module UART_TX
#(parameter CLKS_PER_BIT = 217)
(
    input i_Clock,
    input i_TX_DV,
    input [7:0] i_TX_Byte,
    output o_TX_Active,
    output reg o_TX_Serial,
```

```
output
           o_TX_Done
 );
 parameter IDLE = 3'b000;
 parameter TX_START_BIT = 3'b001;
 parameter TX DATA BITS = 3'b010;
 parameter TX_STOP_BIT = 3'b011;
 parameter CLEANUP
                       = 3'b100;
                               ECE DER
 reg [2:0] r_SM_Main
                        = 0;
 reg [7:0] r_Clock_Count = 0;
 reg [2:0] r_Bit_Index = 0;
 reg [7:0] r TX Data = 0;
       r TX Done
                     = 0;
 reg
 reg
      r_TX_Active = 0;
always @(posedge i Clock)
begin
case (r SM Main)
IDLE :
    begin
                                // Drive Line High for Idle
     o TX Serial <= 1'b1
                    <= 1'b0;
     r TX Done 🔪
     r_Clock_Count <= 0;
     r_Bit_Index <= 0;
     if (i_TX_DV == 1'b1)
     begin
           r TX Active <= 1'b1;
           r_TX_Data <= i_TX_Byte;
          r_SM_Main <= TX_START_BIT;</pre>
       end
     else
     r_SM_Main <= IDLE;
    end //
    case: IDLE
// Send out Start Bit. Start bit = 0
   TX START BIT:
    begin
     o_TX_Serial <= 1'b0;
     // Wait CLKS PER BIT-1 clock cycles for start bit to finish
     if (r_Clock_Count < CLKS_PER_BIT-1)
     begin
       r_Clock_Count <= r_Clock_Count + 1;</pre>
       r_SM_Main <= TX_START_BIT;
       end
       else
       begin
       r_Clock_Count <= 0;</pre>
       r SM Main <= TX DATA BITS;
       end
    end
                 // case: TX START BIT
// Wait CLKS_PER_BIT-1 clock cycles for data bits to finish
   TX DATA BITS :
    begin
```

```
o_TX_Serial <= r_TX_Data[r_Bit_Index];</pre>
if (r _Clock_Count < CLKS_PER_BIT-1)
begin
       r_Clock_Count <= r_Clock_Count + 1;</pre>
       r SM Main <= TX DATA BITS;
       end
       else
       begin
      r_Clock_Count <= 0;</pre>
                                 // Check if we have sent out all bits
   if (r_Bit_Index < 7)
   begin
        r_Bit_Index <= r_Bit_Index + 1;</pre>
        r SM Main <= TX DATA BITS;
        end
       else
       begin
        r_Bit_Index <= 0;
        r SM Main <=
       TX_STOP_BIT;
        end
      end
    end
                          // case: TX DATA BITS
   // Send out Stop bit. Stop bit = 1
    TX STOP BIT :
     begin
      o TX Serial <= 1'b1;
      // Wait CLKS_PER_BIT-1 clock cycles for Stop bit to finish
      if (r Clock Count < CLKS PER BIT-1)
      begin
       r_Clock_Count <= r_Clock_Count + 1;</pre>
       r SM Main <= TX STOP BIT;
       end
       else
       begin
       r_TX_Done
                     <= 1'b1; r_Clock_Count <= 0;
       r_SM_Main
                     <= CLEANUP;
       r TX Active <= 1'b0;
      end
    end // case: TX_STOP_BIT
   // Stay here 1 clock
   CLEANUP:
    begin
      r_TX_Done <= 1'b1;
      r_SM_Main <= IDLE;
      end
   default :
    r_SM_Main <= IDLE;
    endcase
 end
```

assign o\_TX\_Active = r\_TX\_Active; assign o\_TX\_Done = r\_TX\_Done; endmodule Source Code - Receiver : // This file contains the UART Receiver. This receiver is able to // receive 8 bits of serial data, one start bit, one stop bit, // and no parity bit. When receive is complete o rx dv will be // driven high for one clock cycle. // Set Parameter CLKS PER BIT as follows: // CLKS\_PER\_BIT = (Frequency of i\_Clock)/(Frequency of UART) // Example: 25 MHz Clock, 115200 baud UART // (2500000)/(115200) = 217 module UART\_RX #(parameter CLKS PER BIT = 217)( i Clock, input i\_RX\_Serial, input o\_RX\_DV output output [7:0] o\_RX\_Byte ); parameter IDLE = 3'b000; parameter RX START BIT = 3'b001; parameter RX DATA BITS = 3'b010; parameter RX STOP BIT = 3'b011; parameter CLEANUP = 3'b100; reg [7:0] r\_Clock\_Count = 0; reg [2:0] r Bit Index = 0; //8 bits total reg [7:0] r\_RX\_Byte = 0;reg r RX DV = 0; reg [2:0] r\_SM\_Main = 0; // Purpose: Control RX state machine always @(posedge i Clock) begin case (r SM Main) IDLE : Begin r-RX DV <=1'b0; r\_Clock\_Count <= 0; r\_Bit\_Index <= 0;</pre> if (i RX Serial == 1'b0) // Start bit detected r\_SM\_Main <= RX\_START\_BIT;</pre> else r SM Main <= IDLE; end // Check middle of start bit to make sure it's still low **RX START BIT:** begin

```
if (r_Clock_Count == (CLKS_PER_BIT-1)/2)
    begin
     if (i_RX_Serial == 1'b0)
     begin
       r_Clock_Count <= 0; // reset counter, found the middle
                     <= RX DATA BITS;
       r SM Main
       end
                                            OFP
       else
       r_SM_Main <= IDLE;
       end
       else
      begin
    r_Clock_Count <= r_Clock_Count + 1;
    r SM Main
                  <= RX START BIT;
    end
                // case: RX START BIT
   end
  // Wait CLKS_PER_BIT-1 clock cycles to sample serial data
  RX DATA BITS:
   begin
    if (r Clock Count < CLKS PER BIT-1)
    begin
     r Clock Count <= r Clock Count + 1;
     r SM Main <= RX DATA BITS;
     end
    else
    begin
     r Clock Count <= 0;</pre>
     r_RX_Byte[r_Bit_Index] <= i_RX_Serial;
     // Check if we have received all bits
     if (r_Bit_Index < 7)
       begin
       r Bit Index <= r Bit Index + 1;
       r SM Main <= RX DATA BITS;
       end
       else
         begin
                r_Bit_Index <= 0;
                r SM Main <= RX STOP BIT;
                end
  end
                 // case: RX DATA BITS
end
  // Receive Stop bit. Stop bit = 1
  RX_STOP_BIT :
   begin
    // Wait CLKS_PER_BIT-1 clock cycles for Stop bit to finish
    if (r Clock Count < CLKS PER BIT-1)
    begin
     r_Clock_Count <= r_Clock_Count + 1;</pre>
     r SM Main <= RX STOP BIT;
       end
       else
       begin
        r RX DV
                     <= 1'b1;
```

```
r Clock Count <= 0;
      r_SM_Main <= CLEANUP;
      end
    end
                 // case: RX STOP BIT
   // Stay here 1 clock
   CLEANUP:
    begin
                                   r SM Main <= IDLE;
     r_RX_DV <= 1'b0;
    end
   default :
    r SM Main <= IDLE;
        endcase
        end
 assign o_RX_DV = r RX DV;
 assign o_RX_Byte = r_RX_Byte;
 endmodule // UART_RX
Test bench :
// This testbench will exercise the UART RX.
// It sends out byte 0x37, and ensures the RX receives it correctly.
`timescale 1ns/10ps
`include "uart tx.v"
`include "uart rx.v"
module UART_TB ();
 // Testbench uses a 25 MHz clock
 // Want to interface to 115200 baud UART
 // 2500000 / 115200 = 217 Clocks Per Bit.
 parameter c CLOCK PERIOD NS = 40;
 parameter c_CLKS_PER_BIT
                               = 217;
 parameter c_BIT_PERIOD
                             = 8600;
 reg r Clock = 0;
 reg r_TX_DV = 0;
 wire w_TX_Active, w_UART_Line;
 wire w TX Serial;
 reg [7:0] r_TX_Byte = 0;
 wire [7:0] w_RX_Byte;
 UART_RX #(.CLKS_PER_BIT(c_CLKS_PER_BIT)) UART_RX_Inst
  (.i_Clock(r_Clock),
  .i RX Serial(w UART Line),
   .o_RX_DV(w_RX_DV),
   .o_RX_Byte(w_RX_Byte)
   );
 UART TX #(.CLKS PER BIT(c CLKS PER BIT)) UART TX Inst
  (.i Clock(r Clock),
   .i_TX_DV(r_TX_DV),
   .i_TX_Byte(r_TX_Byte),
   .o TX Active(w TX Active),
   .o_TX_Serial(w_TX_Serial),
   .o TX Done()
   );
 // Keeps the UART Receive input high (default) when
```

assign w_UART_Line = w_TX_Active ? w_TX_Serial : 1'b1; always #(c_CLOCK_PERIOD_NS/2) r_Clock <= !r_Clock;	
// Main Testing:	
initial	
begin	
<pre>// Tell UART to send a command (exercise TX) @(posedge r_Clock);</pre>	
@(posedge r_Clock);	
r TX DV <= 1'b1;	
r_TX_Byte <= 8'h3F;	
@(posedge r_Clock);	
r_TX_DV <= 1'b0;	
end	
endmodule	
<u>Waveform :</u>	
Waveform 1 - SimVision	_ = ×
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Eile Edit View Explore Format Simulation Windows Help	cadence
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Fig: Simulation Waveform for UART

#### b) Synthesize the Design

- 1. read\_libs /home/install/FOUNDRY/digital/90nm/dig/lib/slow.lib
- 2. read\_hdl {uart\_tx.v / uart\_rx.v} //Choose any one
- 3. elaborate
- 4. read\_sdc constraints\_top.sdc //Reading Top Level SDC
- 5. set\_db syn\_generic\_effort medium //Setting effort medium
- 6. set db syn map effort medium
- 7. set\_db syn\_opt\_effort medium
- 8. syn\_generic
- 9. syn map
- //Performing Synthesis Mapping and Optimisation 10. syn\_opt
- 11. report\_timing > uart\_timing.rep //Generates Timing report for worst datapath and dumps into file
- 12. report\_area > uart\_area.rep
  - //Generates Synthesis Area report and dumps into a file
- 13. report\_power > uart\_power.rep //Generates Power Report [Pre-Layout]
- 14. report\_qor > uart\_qor.rep
- 15. write\_hdl > uart\_netlist.v //Creates readable Netlist File
- 16. write\_sdc > uart\_sdc.sdc
- //Creates Block Level SDC

Dept. of ECE, CIT, Gubbi

# Synthesis RTL Schematic :

Schematic	-	۰
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	auto upuate	. 2

#### Note :-

1. You can tabulate Area, Power and Timing Constraints using any of theSDC Constraints as instructed.

2. Make sure, during synthesis the Report File Names are changed so that the latest reports donot overwrite the earlier ones.

# Lab 6: Physical Design

**<u>Aim:</u>** For the synthesized netlist carry out the following any two above experiments:

• Floor planning, identify the placement of pads, placement and Routing

#### **Tool Required:**

- Functional Simulation: Incisive Simulator (ncvlog, ncelab, ncsim)
- Synthesis: Genus
- Physical Design: Innovus

Mandatory Inputs for PD:

- 1. Gate Level Netlist [Output of Synthesis]
- 2. Block Level SDC [Output of Synthesis]
- 3. Liberty Files (.lib)
- 4. LEF Files (Layer Exchange Format)

#### Expected Outputs from PD:

- 1. GDS II File (Graphical Data Stream for Information Interchange Feed In for FabricationUnit).
- 2. SPEF, SDF
  - Make sure the Synthesis for the target design is done and open a terminal from the corresponding workspace.
  - Initiate the Cadence tools and cmd :innovus (Press Enter)
  - For Innovus tool, a GUI opens and also the terminal enters into innovus command prompt where in the tool commands can be entered.

Physical Design involves 5 stages as following :

- After Importing Design,
- → Floor Planning
- $\rightarrow$  Power Planning
- $\rightarrow$  Placement
- $\rightarrow$  CTS (Clock Tree Synthesis)
- $\rightarrow$  RoutingModule

#### Importing Design

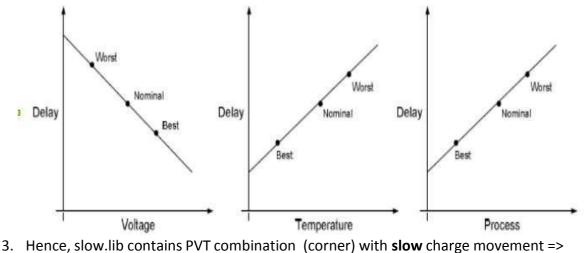
To Import Design, all the Mandatory Inputs are to be loaded and this can be done either using script files named with .globals and .view/.tcl or through GUI as shown below.

The target design considered here is counter design

The procedure shall remain the same for any other design from the above discussed experiments.

#### Note :

- For Synthesis, slow.lib was read as input. Each liberty file contains a pre-defined Process,Voltage and Temperature (PVT) values which impact the ease of charge movement.
- 2. Process, Voltage and Temperature individually affect the ease of currents as depicted below.



# Maximum Delay => Worst Performance

- Similarly, fast.lib contains PVT Combination applicable across its designs to give Fast charge movement => Minimum Delay => Best Performance.
- 5. When these corners are collaborated with the sdc, they can be used to analyse timing forsetup in the worst case and hold in the best case.
- 6. All these analysis views are to be manually created either in the form of script or using theGUI.

```
Generated by:
                         Cadence Encounter 13.23-s047_1
#
  OS:
                         Linux x86_64(Host ID cadence)
#
#
   Generated on:
                         Tue May 24 02:16:38 2016
# Design:
# Command: save_global Default.globals
#
# Version 1.1
#
set ::TimeLib::tsgMarkCellLatchConstructFlag 1
set conf_qxconf_file {NULL}
set conf_qxlib_file {NULL}
set defHierChar {/}
set init design settop 0
set init_gnd_net {VSS}
set init_lef_file {lef/gsclib090_translated.lef lef/gsclib090_translated_ref.lef}
set init_mmmc_file {Default.view}
set init_pwr_net {VDD}
set init_verilog {counter_netlist.v}
set lsg0CPGainMult 1.000000
set pegDefaultResScaleFactor 1.000000
set pegDetailResScaleFactor 1.000000
                             Script under Default.globals file
 # Version:1.0 MMMC View Definition File
 # Do Not Remove Above Line
 create library set -name MAX timing -timing {/root/Desktop/counter/lib/90/slow.lib}
 create_library_set -name MIn_timing -timing {/root/Desktop/counter/lib/90/fast.lib}
create_constraint_mode -name Constraints -sdc_files {counter_sdc.sdc}
 create_delay_corner -name Max_delay -library_set {MAX_timing}
 create_delay_corner -name Min_delay -library_set {MIn_timing}
 create_analysis_view -name Worst -constraint_mode {Constraints} -delay_corner {Max_delay}
 create_analysis_view -name best -constraint_mode {Constraints} -delay_corner {Min_delay}
set_analysis_view -setup {Worst} -hold {best}
```

Script under Default.view (or) Default.tcl file

Note : Check the paths to properly read in the input files.

- Else, if you would like to import your design using GUI, open the Innovus tool and from the
  - GUI, go to File  $\rightarrow$  Import Design.
- A new pop-up window appears.
- First load the netlist. You can browse for the file and select "Top cell : Auto Assign".

Jetlist File:	Netlist Selection:
counter_netlist.v	Add Contraction of the second
Netlist Files:	/root/Desktop/Digital_Manuals/designs/counter/4_bit 🔽 🍋
counter_netlist.v	fv       Ind.var         INCA_libs       Innovus.cmd         waves.shm       innovus.logv         cds.lib       innovus.logv         constraints_top.sdc       ncelab.log         counter_v       nclaunch.key         counter_cell.rep       ncsim.log         counter_power.rep       ncvlog.log         counter_sdc.sdc       pvsU_pvs.log         counter_timing.rep       genus.cmd         genus.log       counter_timing.rep
, ,	Filters: Netlist Files (*.v*)

Similarly select your lef files from /home/install/FOUNDRY/digital/90nm/dig/lef/ as shown below.

	LEF Files	>
LEF File: Dnm/dig/lef/gsclib090_translated_ref.lef	LEF Selection:	
LEF Files:	/home/install/FOUNDRY/digital/90nm/dig/lef	- 🖻
/home/install/FOUNDRY/digital/90nm/dig/lef/gsclil /home/install/FOUNDRY/digital/90nm/dig/lef/gsclil	<pre>doc gsclib090_macro.lef gsclib090_tech.lef gsclib090_translated.lef gsclib090_translated.lef gsclib090_translated_ref.lef</pre>	

Once both the Netlist and LEF Files are loaded, your import design window is as follows.

	Design Import
Netlist:	
Verilog	
Files: o	ounter_netlist.v
	Top Cell: 🖲 Auto Assign 🔾 By User:
O OA	
Library:	
Cell:	
View:	
Technology/Physical Libraries:	
G OA	
Reference Libraries:	
Abstract View Names:	
Layout View Names:	
● LEF Files n	ne/install/FOUNDRY/digital/90nm/dig/lef/gsclib090_translated

• In order to load the Liberty File and SDC, create delay corners and analysis view, select the "Create Analysis Configuration" option at the bottom.

Power Nets:			
Ground Nets:			
CPF File:			E
Analysis Configuration			
MMMC View Definition File:			E
	Create Analysis Configuration	n)	

• An MMMC browser Pops Up.

Analysis View List	MMMC Objects	Wizard Help
⊕ Analysis Views ⊕ Setup Analysis Views ⊕ Hold Analysis Views	Library Sets RC Corners OP Conds Delay Corners Constraint Modes	system for RC extraction, delay calculation, and timing analysis. It you have all the necessary data available, it is recommended that you configure the system as completely as possible for all steps of the implementation flow - through signoff. If not, you can always update the configuration, if necessary, as you proceed through the flow. If you are comfortable using the MMMC Browser, you can use the <b>Wizard Off</b> button to remove the help dialog, and proceed at your own pace.

The order of adding the MMMC Objects is as follows.

- 1. Library Sets
- 2. RC Corners
- 3. Delay Corners
- 4. Constraints (SDC)

Once all of them are added, Analysis Views are created and assigned to Setup and Hold. In order to add any of the objects, make a right click on the corresponding label  $\rightarrow$  Select New.

• Adding Liberty Files under "Library Sets"

ning Library File:	Timing Library Selection:
DUNDRY/digital/90nm/dig/lib/slow.lib	install/FOUNDRY/digital/90nm/dig/lib/
/home/install/FOUNDRY/digital/90nm/dig/lib/slow	fast.lib         fast.lib_ecsm         README         slow.lib_ecsm         ss_0v67.lib         ss_0v75.lib_ecsm         ss_0v75.lib         ss_0v75.lib         typical.lib         typical.lib_ecsm
	Filters: Timing Library Files (*.lib)

	Add Lib	rary Set	+)		×
lame: Slow					
Timing Library Files		SI Library Files			
/home/install/FOUNDRY/					
	Add			Add.	~
	Delete			Delet	ie
		122			
		n so			
	pply	Close	He	In	

- Similarly, add fast.lib with a label Fast or any identifier of your own.
- Adding RC Corners can also be done in a similar process. The temperature value can be found under the corresponding liberty file. Also, cap table and RC Tech files can be addedfrom Foundry where available.

	Add RC Corner	_ = ×
	Name: Max	24
$\langle \mathbf{N}   $	Cap Table	E
Nil	Temperature	125
	PreRoute Resistance Scale Factor:	1.0
	PreRoute Cap Scale Factor:	1.0
	PreRoute Clock Resistance Scale Factor:	0.0
	PreRoute Clock Cap Scale Factor:	0,0
	PostRoute Resistance Scale Factor:	1.0
	PostRoute Cap Scale Factor:	1.0
	PostRoute Xcap Scale Factor:	1.0
	PostRoute Clock Resistance Scale Factor:	0.0
	PostRoute Clock Cap Scale Factor:	0.0
	QRC Technology File	2

	MMMC Browser	
Analysis View List	MMMC Objects	
	E Library Sets E Slow E Fast Fast G RC Corners E Max E Min E OP Conds E Delay Corners E Constraint Modes	

- Delay Corners are formed by combining Library Sets with RC Corners.
- An example is shown below.

Name: Maximum		
Power Domain	List	Туре
default		On Chip Variation  Single/BcWc
Bhohado a bhadan an		Attributes
		RC Corner: Max
		Library Set: Slow
		OpCond Lib:
		IrDrop File:
		Early
	Add	Library Set:
	Delete	OpCond Lib:
		OpCond:
		IrDrop File:
		Late
		Library Set:
		OpCond Lib:
		OpCond:
		IrDrop File
<u>o</u> k	Apply	<u>Close</u> <u>Help</u>
	be read in unde	er the MMMC Object of "Constraints".
	be read in unde	
imilarly, SDC can l	be read in unde SDC	er the MMMC Object of "Constraints".
Similarly, SDC can l	be read in unde	er the MMMC Object of "Constraints".
imilarly, SDC can l onstraint File: er_sdc.sdc Constraint Files:	be read in unde SDC	er the MMMC Object of "Constraints".
imilarly, SDC can l onstraint File: er_sdc.sdc Constraint Files:	be read in unde SDC	er the MMMC Object of "Constraints".
imilarly, SDC can l onstraint File: er_sdc.sdc Constraint Files:	be read in unde SDC	er the MMMC Object of "Constraints".
imilarly, SDC can l onstraint File: er_sdc.sdc Constraint Files:	be read in unde SDC	er the MMMC Object of "Constraints".
Similarly, SDC can l constraint File: er_sdc.sdc Constraint Files:	be read in unde SDC	er the MMMC Object of "Constraints".
Similarly, SDC can l onstraint File: rer_sdc.sdc Constraint Files:	be read in unde SDC	er the MMMC Object of "Constraints".
Similarly, SDC can l onstraint File: rer_sdc.sdc Constraint Files:	be read in unde SDC	er the MMMC Object of "Constraints".
Similarly, SDC can l onstraint File: rer_sdc.sdc Constraint Files:	be read in unde SDC	the MMMC Object of "Constraints".     Constraint Files      SDC Constraint Selection:     /root/Desktop/Digital_Manuals/designs/counter/4_bit     fv     hdl.var     innovus.cmd     innovus.log     cds.lib     innovus.logv     constraints_top.sdc     ncelab.log     counter.v     nclaunch.key     counter_cell.rep     ncsim.log     counter_netlist.v     ncsim.log     counter_power.rep     ncvlog.log     counter_power.rep     ncvlog.log     counter_tstv     ncsim.log     counter_tstv     counter_timing.rep
	be read in unde SDC	er the MMMC Object of "Constraints".
Similarly, SDC can l onstraint File: rer_sdc.sdc Constraint Files:	be read in unde SDC	C Constraint Files

• Analysis Views are formed from combinations of SDC and Delay Corner.

Nar	ne: Best
Constraint Mo	de: constraints
Delay Corr	er: Minimum

and the second second

• Once "Best" and "Worst" Analysis views are created, assign them to Setup and Hold.

Concernence and the control of the c
Add Setup Analysis View _
Analysis View: Worst
OK Apply Close Help
Add Hold Analysis View 🛶 🗖 🗙
Analysis View: Best
OK Apply Close Help

- Once all the process is done, Click on "Save&Close" and save the script generated with any name of your choice.
- Make sure the file extension remains .view or .tcl
- After saving the script, go back to Import Design window and Click "OK" to load your design.

	MMMC Browser	>
Analysis View List	MMMC Objects	Wizard Help
<ul> <li>Analysis Views</li> <li>⊕ Best</li> <li>⊕ Worst</li> <li>⊖ Setup Analysis Views</li> <li>⊕ Worst</li> <li>⊟ Hold Analysis Views</li> <li>⊕ Best</li> </ul>	<ul> <li>⊨ Library Sets</li> <li>⊕ Slow</li> <li>⊕ Fast</li> <li>⊕ Max</li> <li>⊕ Min</li> <li>⊕ OP Conds</li> <li>⊡ Delay Corners</li> <li>⊕ Maximum</li> <li>⊕ Minimum</li> <li>⊕ Minimum</li> <li>⊕ Constraint Modes</li> <li>⊕ constraints</li> </ul>	System for RC extraction, delay calculation, and timing analysis. It you have all the necessary data available, it is recommended that you configure the system as completely as possible for all steps of the implementation flow - through signoff. If not, you can always update the configuration, if necessary, as you proceed through the flow. If you are comfortable using the MMMC Browser, you can use the <b>Wizard Off</b> button to remove the help dialog, and proceed at your own pace. For additional assistance with design import, press the <b>Next</b> button Prev

oorplan				
IO Assignm	ent File:			
ower				
Pow	er Nets: VDD			
Groui	nd Nets: VSS			
c	PF File:			
nalysis Configuratio	n			
MMMC View Defin	ition File: Default.vie	2W		
	Create	e Analysis Configuratio	on )	
ОК	Save	Load	Cancel	Help
		n your GUI if and c	1	
the box does not a	appear, check for	errors in your log (	Either on termina	Il or log file
the box does not a	appear, check for	errors in your log (	Either on termina	I or log file
the box does not a	appear, check for	errors in your log (	Either on termina	I or log file
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the box does not a	appear, check for	errors in your log (	Either on termina	I or log file
the box does not a	appear, check for	errors in your log (	Either on termina	I or log file
the box does not a	appear, check for	errors in your log (	Either on termina	I or log file
the box does not a	appear, check for	errors in your log (	Either on termina	I or log file
adproperly. the box does not a om pwd)	appear, check for	errors in your log (	Either on termina	I or log file

- The internal area of the box is called "Core Area".
- The horizontal lines running along the width of Core are "Standard Cell Rows". Every alternate of them are marked indicating alternate VDD and VSS rows.
- This setup is called "Flipped Standard Cell Rows".

### $\rightarrow$ Floorplan

Steps under Floorplan :

- 1. Aspect Ratio [Ratio of Vertical Height to Horizontal Width of Core]
- 2. Core Utilisation [The total Core Area % to be used for Floor Planning]
- 3. Channel Spacing between Core Boundary to IO Boundary
  - Select Floorplan → Specify Floorplan to modify/add concerned values to the above Factors. On adding/modifying the concerned values, the core area is also modified

	Basic Advanced	4
	Design Dimensions	
	Specify By:  Size  Die/IO/Core Coordinates	
	Core Size by: Aspect Ratio: Ratio (H/W): 0.85739883	
	Core Utilization: 0.699933	
	Cell Utilization: 0.699933	
	O Dimension: Width: 33.485	
	Height: 28.71	
	O Die Size by: Width: 33.485	
	Height: 28.71	
	Core Margins by:  Core to IO Boundary	
	Core to Die Boundary	
	Core to Left: 8 Core to Top: 8	
	Core to Right: 8 Core to Bottom: 8	
	Die Size Calculation Use: O Max IO Height S Min IO Height Floorplan Origin at: E Lower Left Corner C Center	
	Floorplan Origin ac: Scower Left Corner Corner Unit: Micron	
Layout		
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		<u>لا</u>
	Image: Second	× s
	<ul> <li>♥ • W ■ ● ● ● ● ● ● ● ● ● ● ● ● ● ● ● ● ● ●</li></ul>	v s
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	<ul> <li>✓ • W N N N N N N N N N N N N N N N N N N</li></ul>	N K K K K K K K K K K K K K K K K K K K
	<ul> <li>         • • • • • • • • • • • • • • • • • • •</li></ul>	A K K K K K K K K K K K K K K K K K K K
	Al Colors       Al Colors       Image: Color of the second s	V S V V V V V V V V V V V V V V V V V V
	<ul> <li>         • • • • • • • • • • • • • • • • • • •</li></ul>	A K K K K K K K K K K K K K K K K K K K
	Normalization of the second	
	Image: Second	
	Image: Second	
	Image:	
	Image: Second	K C K K K K K K K K K K K K K K K K K K
	Image: Second	K K C K K K K K K K K K K K K K K K K K
	Image:	
	Image: Solution of the second sec	K K C K K K K K K K K K K K K K K K K K
	Image: Section of the sec	K K K K C = K = F K K K K K K K K K K K K K K K K
	Image: Image	K K K K C = K = F K K K K K K K K K K K K K K K K
	Image: Second secon	

• The Yellow patch on the Left Bottom are the group of "Unassigned pins" which are to be placed along the IO Boundary along with the Standard Cells [Gates].

## $\rightarrow$ Power Planning

Steps under Power Planning :

- 1. Connect Global Net Connects
- 2. Adding Power Rings
- 3. Adding Power Strings
- 4. Special Route

Under Connect Global Net Connects, we create two pins, one for VDD and one for VSS connecting them to corresponding Global Nets as mentioned in Globals file / Power and Ground Nets.

- 1. Select Power → Connect Global Nets.. to create "Pin" and "Connect to Global Net" asshown and use "Add to list".
- 2. Click on "Apply" to direct the tool in enforcing the Pins and Net connects to Design and then Close the window.

onnection List	Power Ground Connection	
DD:PIN:*.VDD:Module{}	Connect	
SS PIN * VSS:Module()	Pin	
	C Tie High	
	C Tie Low	
	Instance Basename: *	
	Pin Name(s): VSS	
	O Net Basename:	
	Scope	
0	C Single Instance:	
0	💌 Under Module:	
	O Under Power Domain:	1
	Under Region: Ib. 0.0 Hy 0.0 unc 0.0	ury: 0.0
	G Apply All	Contraction of the second
	To Global Net: VSS	
	Override prior connection	
	U Verbose Output	
5 m 7 m	Add to List Update	Delete

- In order to Tap in Power from a distant Power supply, Wider Nets and Parallel connectionsimprove efficiency. Moreover, the cells that would be placed inside the core area are expected to have shorter Nets for lower resistance.
- Hence Power Rings [Around Core Boundary] and Power Stripes [Across Core Boundary]are added which satisfies the above conditions.
- Select Power → Power Planning → Add Rings to add Power rings 'around Core Boundary'.



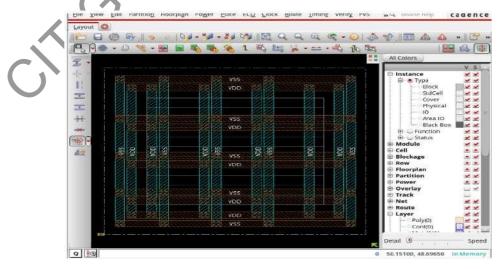
- Select the Nets from Browse option OR Directly type in the Global Net Names separated by a space being Case and Spelling Sensitive.
- Select the Highest Metals marked 'H' [Horizontal] for Top and Bottom and Metals marked 'V' [Vertical] for Right and Bottom. This is because Highest metals have Highest Widths and thus Lowest Resistance.
- Click on Update after the selection and "Set Offset : Centre in Channel" in order to get the Minimum Width and Minimum Spacing of the corresponding Metals and then Click "OK".

• Similarly, Power Stripes are added using similar content to that of Power Rings



Factors to be considered under Power Stripes :

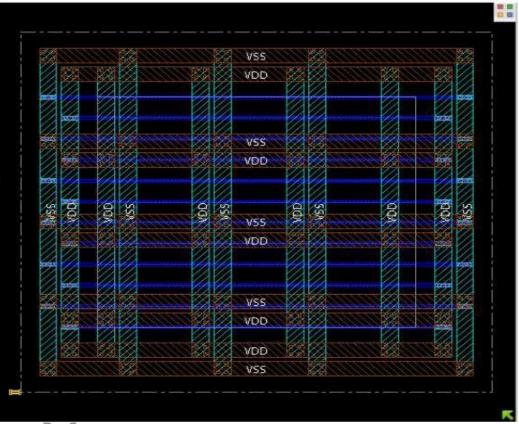
- $\rightarrow$  Nets
- $\rightarrow$  Metal and It's Direction
- → Width and Spacing [Updated]
- $\rightarrow$  Set to Set Distance = ( Minimum Width of Metal + Min. Spacing ) x 2



- On adding Power Stripes, The Power mesh setup is complete as shown. However, There are no Vias that could connect Metal 9 or Metal 8 directly with Metal 1 [VDD or VSS of Standard Cells are generally made up of Metal 1].
- The connection between the Highest and Lowest Metals is done through Stacking of Vias done using "Special Route".
- To perform Special Route, Select Route  $\rightarrow$  Special Route  $\rightarrow$  Add Nets  $\rightarrow$  OK.
- After the Special Route is complete, all the Standard Cell Rows turn to the Color coded forMetal 1 as shown below.

The complete Power Planning process makes sure Every Standard Cell receives enough power tooperate smoothly.

#### $\rightarrow$ Pre – Placement :



- After Power Planning, a few Physical Cells are added namely, End Caps and Well Taps.
- <u>End Caps</u>: They are Physical Cells which are added to the Left and Right Core Boundariesacting as blockages to avoid Standard Cells from moving out of boundary.
- <u>Well Taps :</u> They act like Shunt Resistance to avoid Latch Up effects.

To add End Caps, Select Place  $\rightarrow$  Physical Cell  $\rightarrow$  Add End Caps and "Select" the FILL's from the available list.

- Higher Fills have Higher Widths. As shown Below, The End Caps are added below yourPower Mesh.
- To add Well Taps, Select Place → Physical Cell → Add Well Tap → Select → FillX [X → Strength of Fill = 1,2,4 etc] → Distance Interval [Could be given in range of 30-45u] → OK

) @ ={   > *	Q <b>4 * 4 • </b> # 4 Q	1 I I Q	a a c. • 0	👶 🏫 🔟 🏔 🛽	s 🛛 🎦
• 🗘 💘 • 🕅	R 8 R 2 1		·	A REAL PROPERTY AND A REAL	II & (
A HOUSE			W EHS	All Colors	
					11.5
				E Row	V S
				🕑 Row	
				Partition	• •
				D Power	
0			13	Dverlay	57
8			100	1 Track	1.1
				1 Net	¥ 4
<u>H</u>				Route	* *
				🖯 Layer	
				Poly(0)	
8				- Cont(0)	
				Metal1(1)	
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				Metal4(4)	
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8				- Via5(5)	
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				Metal7(7)	Nº 4
				Via7(7)	

Dept. of ECE, CIT, Gubbi

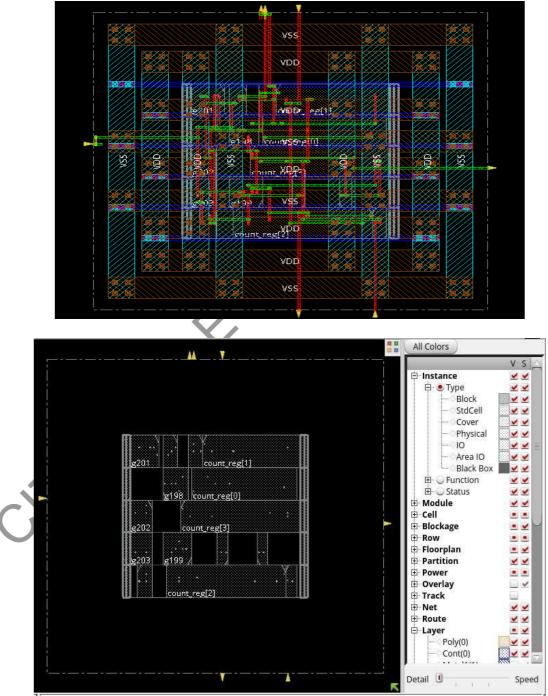
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#### $\rightarrow$ Placement

- 1. The Placement stage deals with Placing of Standard Cells as well as Pins.
- 2. Select Place  $\rightarrow$  Place Standard Cell  $\rightarrow$  Run Full Placement  $\rightarrow$  Mode  $\rightarrow$  Enable 'Place I/O Pins'  $\rightarrow$  OK  $\rightarrow$  OK .

	Place	_ ¤ ×
💌 Run Full	Placement 😳 Run Incremental Placement 😳 Run Placeme	nt In Floorplan Mode
	on Options Pre-Place Optimization	
Number of L	ocal CPU(s): 1 Set Multiple CPU	
ОК	Apply Mode Defaults Cano	el <u>H</u> elp
	Mode Setup	- 0
st of Modes	Placement Mode	
TS	Placement RefinePlace	
indcap iiller VanoRoute DasisOut optimization <u>Vatenkint</u> icanReorder treamOut TeHILo	Low Medium High Auto     Run Flacement In FloorFlan Mode     Run Flacement In FloorFlan Mode     Run Flacement Enable Module Plan     Enable Module Plan     Enable Clock Gating Awareness     Enable Power Driven     Ignore Scan Connections     Roorder Scan Connection     Ignore Spare Cell Connections     Place IO Plins     Hierarchy Aware Spare Cell Placement     Specify Maximum Density     Layers Checked For Pin Access     Specify Maximum Routing Layer 1	Select
	Set Defaults	

• All the Standard Cells and Pins are placed as per the communication between them, i.e., Two communicating Cells are placed as close as possible so that shorter Net lengths can be used for connections as Shorter Net Lengths enable Better Timing Results.



• You can toggle the Layer Visibility from the list on the Right. The List of Layers available are shown on the right under "Layer" tab with colour coding.

# $\rightarrow$ <u>Report Generation and Optimization</u> :

- 1. Timing Report :
  - 1. To generate Timing Report, Timing  $\rightarrow$  Report Timing  $\rightarrow$  Design Stage PreCTS
  - 2. Analysis Type Setup  $\rightarrow$  OK
  - 3. The Timing report Summary can be seen on the Terminal.
- 2. Area Report :
  - 1. cmd:report\_area
- 3. Power Report :
  - 1. **cmd :** report\_power

```
innovus 9> innovus 9> report_area
Depth Name #Inst Area (um^2)
0 counter 15 134.7282
```

Setup mode			-+		
+	all				
TNS () Violating Pa	ns):  0.605 ns):  0.000 ths:  0 ths:  16	0.000			
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				Nr nets(terms)	
max_tran max fanout			0.000	0 (0) 0 (0) 0 (0) 0 (0)	
User-Defined Activit Activity File: N.A. Hierarchical Global	Activity: N.A N.				
Primary Input Activi Default icg ratio: N Global Comb ClockGat	1.A.				
Primary Input Activi Default icg ratio: N	N.A. Te Ratio: N.A.				
	Power View : Worst User-Defined Activit Activity File: N.A.	<pre>Nr nets(ter max_cap   0 (0) max_tran   0 (0) max_fanout   0 (0) max_length   0 (0) max_length   0 (0) Power View : Worst User-Defined Activity : N.A. Activity File: N.A.</pre>	DRVs Nr nets(terms)   Wo max_cap   0 (0)   max_tran   0 (0)   max_fanout   0 (0)   max_length   0 (0)   Power View : Worst User-Defined Activity : N.A. Activity File: N.A. Hierarchical Global Activity: N.A.	DRVs       Nr nets(terms)       Worst Vio         max_cap       0 (0)       0.000         max_fran       0 (0)       0.000         max_fanout       0 (0)       0         max_length       0 (0)       0         Very Power View : Worst       Very Power View : Worst         User-Defined Activity : N.A.         Activity File: N.A.         Hierarchical Global Activity: N.A.	DRVs       Nr nets(terms)       Worst Vio       Nr nets(terms)         max_cap       0 (0)       0.000       0 (0)         max_tran       0 (0)       0.000       0 (0)         max_fanout       0 (0)       0.000       0 (0)         max_length       0 (0)       0       0 (0)         Power View : Worst       User-Defined Activity : N.A.         Activity File: N.A.         Hierarchical Global Activity: N.A.

- In case of any Violating paths, the design could be optimized in the following way.
- To optimize the Design, Select ECO → Optimize Design → Design Stage [PreCTS] → Optimization Type – Setup → OK



- After you run the optimization, the terminal displays the latest Timing report and updated area and power reports can be checked.
- This step Optimizes your design in terms of Timing, Area and Power. You can GenerateTiming, Area, Power in similar way as above report Post Optimization to compare theReports.

### **Clock Tree Synthesis**

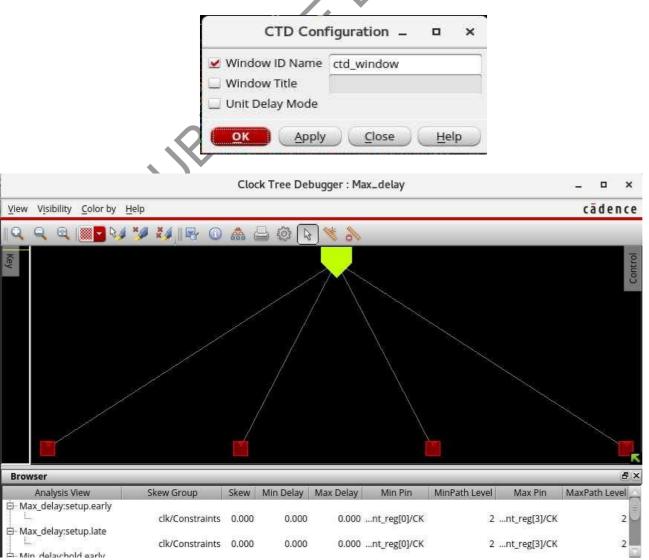
- The CTS Stage is meant to build a Clock Distribution Network such that every Register (Flip Flop) acquires Clock at the same time (Atleast Approximately) to keep them in propercommunication.
- A Script can be used to Build the Clock Tree as follows :

## extractRC

add\_ndr -width {Metall 0.12 Metal2 0.14 Metal3 0.14 Metal4 0.14 Metal5 0.14 Metal6 0.14 Metal7 0.14 Metal8 0.14 Metal9 0.14 } -spacing {Metal1 0.12 Metal2 0.14 Metal3 0.14 Metal3 0.14 Metal5 0.14 Metal6 0.14 Metal7 0.14 Metal8 0.14 Metal9 0.14 } -name 2w2s create\_route\_type -name clkroute -non\_default\_rule 2w2s -bottom\_preferred\_layer Metal5 -top\_preferred\_layer Metal6

set\_ccopt\_property route\_type clkroute -net\_type trunk
set\_ccopt\_property route\_type clkroute -net\_type leaf
set\_ccopt\_property buffer\_cells {CLKBUFX8 CLKBUFX12}
set\_ccopt\_property inverter\_cells {CLKINVX8 CLKINVX12}
set\_ccopt\_property clock\_gating\_cells TLATNTSCA\*
create ccopt\_clock tree spec -file\_ccopt.spec

• Source the Script as shown in the above snapshot through the Terminal and then Select Clock → CCOpt Clock Tree Debugger → OK to build and view clock tree.



- The Red Boxes are the Clock Pins of various Flip Flops in the Design while Yellow Pentagon on the top represents Clock Source.
- The Clock Tree is built with Clock Buffers and Clock Inverters added to boost up the ClockSignal.

Report Generation and Design Optimization :

• CTS Stage adds real clock into the Design and hence "Hold" Analysis also becomes prominent. Hence, Optimizations can be done for both Setup & Hold, Timing Reports are tobe Generated for Setup and Hold Individually.

# Setup Timing Analysis :

	Timing Analysis 🗕 🗖
	Basic Advanced
	Use Existing Extraction and Timing Data
	Design Stage
	C Pre-Place Pre-CTS Post-CTS Post-Route Sign-Off
	Analysis Type
	Setup
	Reporting Options
	Number of Paths: 50
	Depart file/a) Deafler counter part/TC
	Report file(s) Prefix: counter_postCTS
	Report file(s) Prefix:       counter_postCTS         Output Directory:       timingReports
<u>Iold Timing Analysi</u>	Output Directory: timingReports
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For Area and Power Report Generation,

report\_area & report\_power commands can be used.

Design Optimizations :		Optimizati	on –	۰	×
	Oesign Stage	Post-CTS	Post-Route		
	Optimization Type	🕑 H	Hold		
	<ul> <li>Design Rules Viola</li> <li>Max Cap</li> </ul>	tions			
	Max Tran				

# Routing :

- 1. All the net connections shown in the GUI till CTS are only based on the Logical connectivity.
- 2. These connections are to be replaced with real Metals avoiding Opens, Shorts, Signal Integrity [Cross Talks], Antenna Violations etc.
- 3. To run Routing, Select Route → Nano Route → Route and enable Timing Driven and SI Driven for Design Physical Efficiency and Reliability.

Routing Phase		
🖌 Global Route		
Z Detail Route Start	Iteration default End Iteration default	
Post Route Optimization	📃 Optimize Via 📃 Optimize Wire	
Concurrent Routing Fe	atures	
👱 Fix Antenna	🖵 Insert Diodes 🛛 Diode Cell Name	
Z Timing Driven	Effort 5 Congestion Timing S.M	A.R.T.
SI Driven		
Post Route SI	SI Victim File 🕒	
_ Litho Driven		
🔄 Post Route Litho Rep	air	
Routing Control		
Selected Nets Only	Bottom Layer default Top Layer default	- T
ECO Route		
🛄 Area Route	Area	rea and Route
Job Control		
🧟 Auto Stop		
Number	of Local CPU(s): 1	
Number of CPU(s) per R	emote Machine: 1	
Number of Ren	note Machine(s): 0	
Set Multiple CPU		

**Report Generation and Design Optimization :** 

Setup Report :	Timing Analysis _ D
	Basic Advanced
	Use Existing Extraction and Timing Data
	Design Stage
	O Pre-Place O Pre-CTS O Post-CTS Post-Route O Sign-Off
	Analysis Type
	🖲 Setup 🙄 Hold
	🖵 Include SI
	Reporting Options
	Number of Paths: 50
	Report file(s) Prefix: counter_postRoute
	Action and a second sec
	Output Directory: TimingReports
Hold Report :	Output Directory: timingReports
-lold Report :	Output Directory: timingReports OX Apple Cancel Hole Timing Analysis _ 0 Basic Advanced
Hold Report :	Output Directory: timingReports OX Assists Cancel Hole Timing Analysis _ 0 Basic Advanced Use Existing Extraction and Timing Data
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lold Report :	Output Directory: timingReports
lold Report :	Output Directory: timingReports
lold Report :	Output Directory: timingReports
Hold Report :	Output Directory: timingReports
Hold Report :	Output Directory:       timingReports         Image: Concol       Lining         Timing Analysis

### Area and Power Reports :

Use the commands report\_area and report\_power for Area and PowerReports respectively.

```
Design Optimization :
```

```
innovus 5>
innovus 5> setAnalysisMode -analysisType onChipVariation -cppr both
innovus 6> □
```

Enter the above shown command in the Terminal in order to run the Design Optimization first Post-Route.

	Optimizati	on	-	>
Design Stage				_
Pre-CTS	O Post-CTS	e Post-Ro	ute	
Optimization Ty	/pe			
🛃 Setup	🖌 H	lold		
Incremental				
Design Rules \	Violations			
⊻ Max Cap				
👱 Max Tran				
📃 Max Fanout				
Include CI   C	Options			

- As an alternate to the setAnalysisMode command, you can use the GUI at Tools → SetMode → Set Analysis Mode → Select On-Chip-Variation and CPPR.
- The Report generation is same as shown prior to Design Optimization.

# Saving Database :

 Saving Design => File → Save Design → Data Type : Innovus → <DesignName>.enc → OK



2. Saving Netlist => File  $\rightarrow$  Save  $\rightarrow$  Netlist  $\rightarrow$  <NetlistName>.v  $\rightarrow$  OK

	Save Netlist -		×
🖌 Includ	le Intermediate Cell D	efiniti	on
⊻ Includ	le Leaf Cell Definition		

It is recommended to save Netlist and Design at every stage. To restore a Design Data Base, type source <DesignName>.enc in the terminal.

3. S	aving	GDS =>	File →	Save →	GDS/	OASIS →	<filename></filename>	.gds → OK
------	-------	--------	--------	--------	------	---------	-----------------------	-----------

		GDS/OASI	S Export		-		×
Output Form	nat	GDSII/Stream	O OASI	s			
Output File	couont	er_route.enc					822
Map File	stream	Out.map					25
Library Nam	e Desig	gnLib					
Structure	Name	counter					
Attach Inc			umbor				
Attach Nei	tance N t Name	lame to Attribute Numbe		🛄 Uniq	ulfy Ce	ell Nar	nes
Attach Ne Merge File	tance N t Name is	lame to Attribute N		🖵 Uniq	ulfy Ce	ell Nar	nes

### Physical Verification – Capturing DRC and LVS :

- After saving the routed Database, you can proceed for Physical Verification and capture the DRC and LVS reports.
- Inputs Required DRC :
  - Technology Library and Rule Set
  - GDS format giles of all Standard Cells (Given by Cadence at /home/install/FOUNDRY/90nm/dig/gds for 90nm Tech node)
    - Outputs DRC :

- DRC Violation Report
- Physical Netlist (Optional)

From the Innovus GUI, select PVS  $\rightarrow$  Run DRC to open the "DRC Submission Form".

PVS 16.12-64b D	RC Run Submission Form ×
<u>File Preferences Tools Ioolbars H</u> elp	cädenco
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Run Data	
Run Directory PVS_RUN/DRC	
Run Dota Processing	
Bun PVS Single CPU	
Rules Run PVS on Local host	
Ucense Timeout, sec	
Input PVSUI Log Rike PVS. RUN/DRC/pvsuidrc.log	(m)
0	
Dutput	
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DRC Options	
✓ Start DE	
o DRCDE	
PVS RV	
Cancel	
APP	
Submit	
	Technology does not Contain Any GuiPreset Files

The DRC Run Submission Form begins with mentioning the Run Directory. The Run Directory is the location where all the logs, reports and other files concerned with PVS are saved.

	PVS 16.12-64b DRC Run Submission Form	_ = ×
Ale Preference	es Tools Toolbars Help	câdence
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-	Rules	
(And the second	Tech&Rules Configurator	
Run Data	Technology	
2.0	Technology mapping file ./Physica_Venficetion/pytech.lib	
Rules	Technology gpdk090	S
	Rule Set default	
$\odot$	Rules	
Input	Rules File(s)	Add
0		(Remove)
Output	"Physical_Yerification/PVS_RULES/dec.pvi Technology	
印		
DRC Options		( )
one options		
🗹 Start DE		<u>_</u>
DRC DE		( * )
PVS RV		
U PVS RV		
<u>Cancel</u>		View
		View Edit- Log File

Technology does not Contain Any GuiPreset Files

The technology Library is to be loaded under "Rules tab".

- The Technology Library is specific for PVS Tool and technology node on which the designis created.
- On reading the tech lib, the rule set is loaded and the corresponding fabrication rules areread in to be checked against the design.

	PVS 16.12-64b DRC Run Submission Form	_ = ×
Ale Preferenc	es Tools Toolbars Help	cādence
00	) 🖉 🕼 🕲 🛱 📕 🕼	
	Rules	
<u>r</u>	Tech&Rules Configurator	
Run Data	Technology	
	Technology mapping file ./Physica_Venfication/pvtechulib	
Rules	Technology gp0k090	
	Rule Set default	-
$\odot$	Rules	
Input	Rules File(s)	Ada
0		Remove
Output	"Physical Verification/PVS_RULES/dr.c.pri Technology	
1		
DRC Options		()
one options		
🛃 Start DE		
DRC DE		
🔵 PVS RV		
Concel		View
Cancel		
Apply		Edit Log File

• The GDS format files of all standard cells available with the corresponding technology nodeare also provided by the vendor. Select all of them to add.

<u>Ple</u> Preference	is Tools Toolbars Help	cādenc
116 🖬 🕲	🖉    🗟 🗞 🖏 🕎 🗐    🖳	
1967	Layout	
<b>B</b>	Top Cell Name Counter	
Run Data	Create GDSII PVS_RUN/DRC/counter.gds.gz	(
0.0	Merge File(s)	Adl
Rules		Remove
0	/Physical_Ventication/gdt/ACHCONC2.gds	E Chemove
	/Physical_Venikation/gdvAODFWI_gits ./Physical_Venification/gds/AODFW2_gits	~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~
input	./Physical Verification/gdb/AD0HX4 gdb	(Vev
0	JP Invisial Venification/gds/ADDFHVL.gds	
Output	Layout Options	<u> </u>
開	Map File/Physical Verification/STREAM_MAP/90nmNew_streamOut.map	( ) ( Yiew )
DRC Options	The second se	
	Uniquify Cell Names 🔛 With Prefix	
	DBUAUU 2000	
	Additional setStreamOutMode Parameters	
🖌 Start DE	Additional stream Out Parameters	
• DRC DE		
O PVS RV		
	🖵 Area to Check on Layout	Selection Mewar
Cancel	📃 Ridten Input Hierarchy	
Apply	🖌 Abort on Layout Error	

• The output report can be named and saved as shown.

	PVS 16.12-64b DRC Run Submission Form	_ = ×
<u>File</u> <u>P</u> reference	s Tools Toolbars Help	cādence
	🔑 i 🗟 🗞 🗒 😫 i 🙀	
_	Output	
( T	Report	
Run Data	Name counter.sum	
340	Limit 1000	
Rules	🖲 Replace File 💪 Append To File 🔚 Statistics by Cell	
0	Output Format ASCII PVS_RUN/DRC/counter.drc_errors.ascii	
Input	Output Errors Hierarchically Rules Definition	
0	Use Walvers for DRC Checks	
Output	U DRC DE 🕘 Batch	
雨	Serup	
DRC Options	Watwer Hire(s)	
		View
👱 Start DE	Applied Walvers PVS_RUN/DRC/counter.drc_enersascii.waivers.applied	
🖲 DRC DE	Rejected Waivers PVS RUN/DRC/counter.drc.en ors.ascii.waivers rejected	
O PVS RV	Tolerance, UK 0 Magnify in	Save Setup as
<u>Cancel</u> Apply	Add Suffix to Cells	
Submit	Vertices Per Polygon 4096	
		Technology does not Contain Any GuiBraset Dies

# • Hit "Submit" to run the DRC and the following windows appear.

TWO LAYER BOOLEAN: Cumulative Time CPU =     0 (s) REAL =     0 (s)       POLKCON TOPOLOGICAL: Cumulative Time CPU =     0 (s) REAL =     0 (s)       POLYGON MEASUREMENT: Cumulative Time CPU =     0 (s) REAL =     0 (s)       SIZE: Cumulative Time CPU =     0 (s) REAL =     0 (s)       EDGE TOPOLOGICAL: Cumulative Time CPU =     0 (s) REAL =     0 (s)       EDGE TOPOLOGICAL: Cumulative Time CPU =     0 (s) REAL =     0 (s)       EDGE MEASUREMENT: Cumulative Time CPU =     0 (s) REAL =     0 (s)       EDGE MEASUREMENT: Cumulative Time CPU =     0 (s) REAL =     0 (s)	_ • ×
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STAMP: Cumulative Time CPU = 0 (a) RRAL = 0 (a) OKE LAYEE DRC: Cumulative Time CPU = 0 (a) RRAL = 0 (a) TWO LAYEE DRC: Cumulative Time CPU = 0 (a) RRAL = 0 (a) DENSITY: Cumulative Time CPU = 0 (a) RRAL = 0 (a) DENSITY: Cumulative Time CPU = 0 (a) RRAL = 0 (a) CCNNECT: Cumulative Time CPU = 0 (a) RRAL = 0 (a) DENSITY: Cumulative Time CPU = 0 (a) RRAL = 0 (a) ERC: Cumulative Time CPU = 0 (a) RRAL = 0 (b) RATTERN MATCH: Cumulative Time CPU = 0 (a) RRAL = 0 (b) DFM FILL: Cumulative Time CPU = 0 (a) RRAL = 0 (b) DFM FILL: Cumulative Time CPU = 0 (a) RRAL = 0 (b) DFM FILL: Cumulative Time CPU = 0 (b) RRAL = 0 (c) DFM FILL: Cumulative Time CPU = 0 (a) RRAL = 0 (b) Total CPU Time : 2 (b) Total CPU Time : 3 (b) Peak Memory Used : 20 (M) Total DRC RuleDecks : 1607 Total DRC RuleDecks : 1607 Total DRC RuleDecks : 1607 Total DRC RuleDecks is / 150 (15) Summary can be found in file counter.sum ASCII report database is /home/saramyati/Decktop/ASP_design/4_bit/PVS_RUM/drc/counter.drc_errors.ascii Checking in all SoftBhare licenses.	
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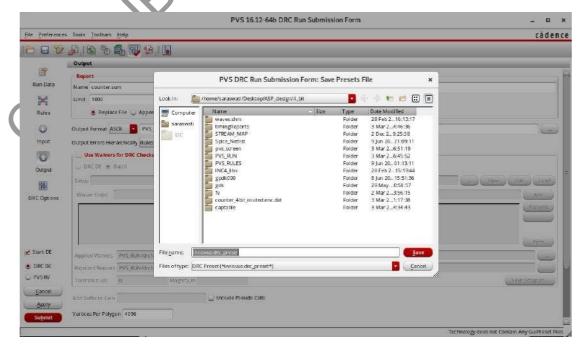
• All the list of DRC Errors can be seen in the above window of which the location of the DRC Violation occuring can be highlighted dealing one to one.

### VLSI LAB 21ECL66

### 2023-2024

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- For example, in the above shown snapshot, the errors associated with N-Implant can be seen. (Select a error occurrence and click on the right arrow below to highlight/zoom in thelocation.)
- You can save the DRC Run as a "Preset" file to rerun the DRC if required at a later point of time.
- Saving/loading the Preset File is shown below.

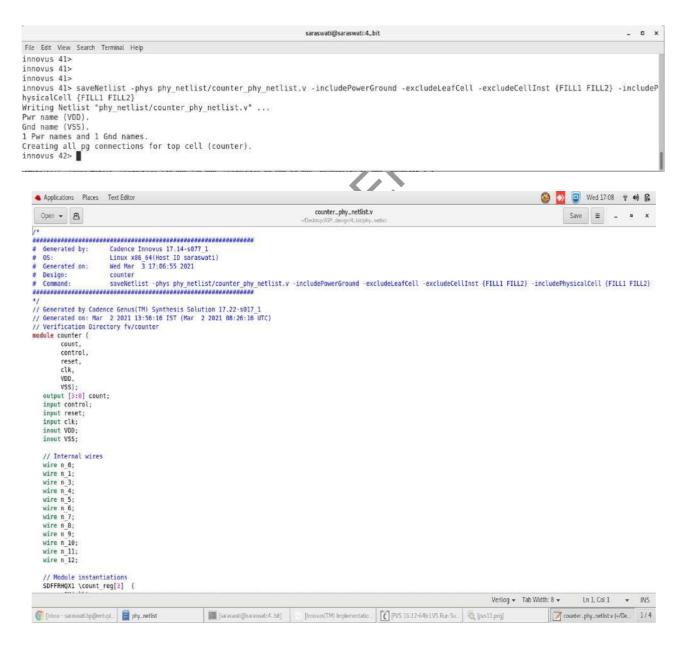


• Loading a Preset file is shown below.



#### Dept. of ECE, CIT, Gubbi

# **Note :** A Physical Netlist can be saved after the DRC Run as shown below.



- Inputs Required LVS :
  - Technology Library
  - Standard Cell GDS Files
  - o Spice Netlist of all Standard Cells (Provided by Library Vendor)
- Outputs LVS :
  - LVS Match/Mismatch Report
- From the Innovus GUI, Select PVS  $\rightarrow$  Run LVS to open the LVS run submission form.

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- Provide the Run directory and log file name (Along with path Optional) •
- Load the Tech Lib, GDS Files and Spice Netlist of all Standard Cells under the corresponding technology node.

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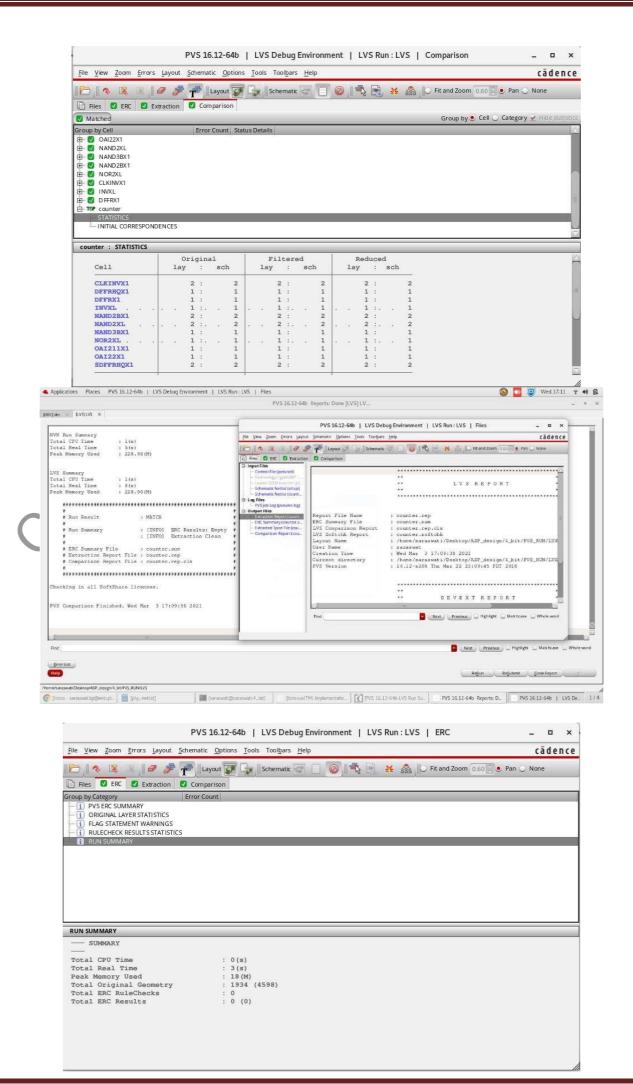
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• On successful completion of LVS Run, the following windows appear.

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- You can create a GDS file along with Stream out file either using the GUI as File  $\rightarrow$  Save  $\rightarrow$  GDS/Oasis or use the following command.
- Cmd : streamOut <GDSFileName>.gds -streamOut <streamOut>.map